

64M bits SDRAM

EDS6432AFBH, EDS6432CFBH (2M words × 32 bits)

Description

The EDS6432AFBH, EDS6432CFBH are 64M bits SDRAMs organized as 524,288 words × 32 bits × 4 banks. All inputs and outputs are synchronized with the positive edge of the clock.

Supply voltages are 3.3V (EDS6432AFBH) and 2.5V (EDS6432CFBH).

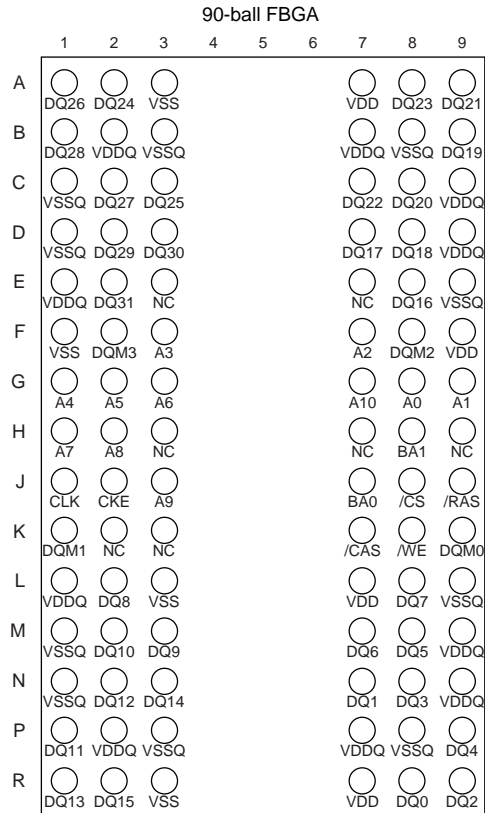
They are packaged in 90-ball FBGA.

Features

- 3.3V and 2.5V power supply
- Clock frequency: 166MHz/133MHz (max.)
- Single pulsed /RAS
- ×32 organization
- 4 banks can operate simultaneously and independently
- Burst read/write operation and burst read/single write operation capability
- Programmable burst length (BL): 1, 2, 4, 8, full page
 - Sequential (BL = 1, 2, 4, 8, full page)
 - Interleave (BL = 1, 2, 4, 8)
- Programmable /CAS latency (CL): 2, 3
- Byte control by DQM
- Refresh cycles: 4096 refresh cycles/64ms
 - Auto refresh
 - Self refresh
- FBGA package with lead free solder (Sn-Ag-Cu)
 - RoHS compliant

Pin Configurations

/xxx indicate active low signal.



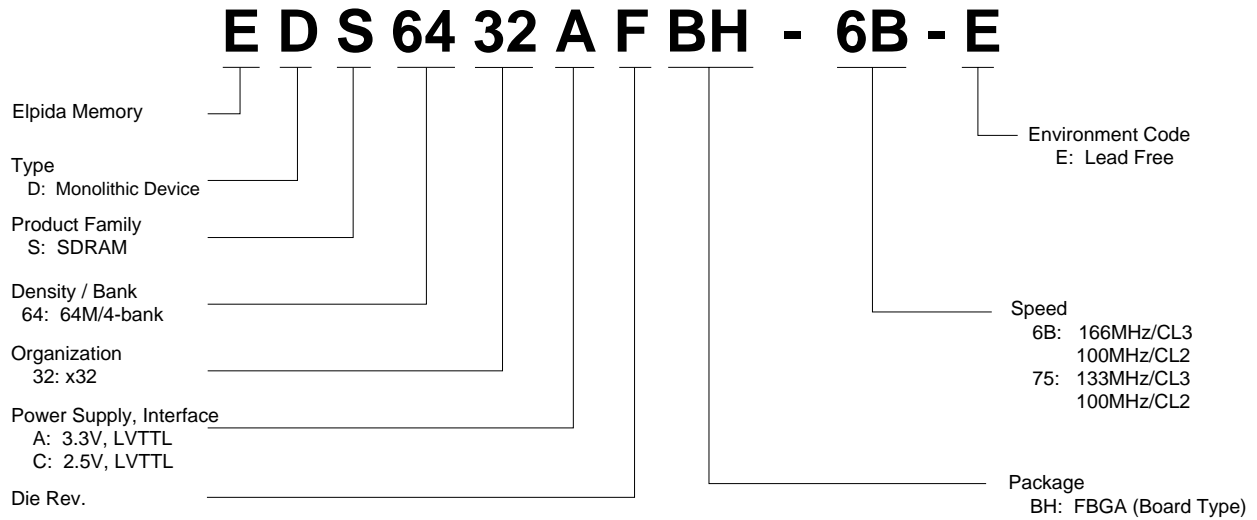
(Top view)

| | |
|--------------|-----------------------------|
| A0 to A10 | Address inputs |
| BA0, BA1 | Bank select address |
| DQ0 to DQ31 | Data-input/output |
| /CS | Chip select |
| /RAS | Row address strobe |
| /CAS | Column address strobe |
| /WE | Write enable |
| DQM0 to DQM3 | DQ mask enable |
| CKE | Clock enable |
| CLK | Clock input |
| VDD | Power for internal circuit |
| VSS | Ground for internal circuit |
| VDDQ | Power for DQ circuit |
| VSSQ | Ground for DQ circuit |
| NC | No connection |

Ordering Information

| Part number | Supply voltage | Organization (words × bits) | Internal Banks | Clock frequency MHz (max.) | /CAS latency | Package |
|------------------|----------------|-----------------------------|----------------|----------------------------|--------------|--------------|
| EDS6432AFBH-6B-E | 3.3V | 2M × 32 | 4 | 166 | 3 | 90-ball FBGA |
| | | | | 100 | 2 | |
| EDS6432AFBH-75-E | 2.5V | 2M × 32 | 4 | 133 | 3 | |
| EDS6432CFBH-75-E | | | | 100 | 2 | |

Part Number



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Electrical Specifications

- All voltages are referenced to VSS (GND).
- After power up, execute power up sequence and initialization sequence before proper device operation is achieved (refer to the Power up sequence).

Absolute Maximum Ratings

| Parameter | Symbol | Rating | Unit | Note |
|---|--------|----------------------------------|------|------|
| Voltage on any pin relative to VSS [EDS6432AF] | VT | -0.5 to VDD + 0.5 (≤ 4.6 (max.)) | V | |
| [EDS6432CF] | VT | -0.5 to VDD + 0.5 (≤ 3.6 (max.)) | V | |
| Supply voltage relative to VSS [EDS6432AF] | VDD | -0.5 to +4.6 | V | |
| [EDS6432CF] | VDD | -0.5 to +3.6 | V | |
| Short circuit output current | IOS | 50 | mA | |
| Power dissipation | PD | 1.0 | W | |
| Operating ambient temperature | TA | 0 to +70 | °C | |
| Storage temperature | Tstg | -55 to +125 | °C | |

Caution

Exposing the device to stress above those listed in Absolute Maximum Ratings could cause permanent damage. The device is not meant to be operated under conditions outside the limits described in the operational section of this specification. Exposure to Absolute Maximum Rating conditions for extended periods may affect device reliability.

Recommended DC Operating Conditions (TA = 0°C to +70°C)

[EDS6432AF]

| Parameter | Symbol | min. | max. | Unit | Notes |
|--------------------|-----------|------|-----------|------|-------|
| Supply voltage | VDD, VDDQ | 3.0 | 3.6 | V | 1 |
| | VSS, VSSQ | 0 | 0 | V | 2 |
| Input high voltage | VIH | 2.0 | VDD + 0.3 | V | 3 |
| Input low voltage | VIL | -0.3 | 0.8 | V | 4 |

- Notes: 1. The supply voltage with all VDD and VDDQ pins must be on the same level.
 2. The supply voltage with all VSS and VSSQ pins must be on the same level.
 3. VIH (max.) = VDD + 1.5V (pulse width ≤ 5ns).
 4. VIL (min.) = VSS - 1.5V (pulse width ≤ 5ns).

[EDS6432CF]

| Parameter | Symbol | min. | max. | Unit | Notes |
|--------------------|-----------|------|-----------|------|-------|
| Supply voltage | VDD, VDDQ | 2.3 | 2.7 | V | 1 |
| | VSS, VSSQ | 0 | 0 | V | 2 |
| Input high voltage | VIH | 1.7 | VDD + 0.3 | V | 3 |
| Input low voltage | VIL | -0.3 | 0.7 | V | 4 |

- Notes: 1. The supply voltage with all VDD and VDDQ pins must be on the same level.
 2. The supply voltage with all VSS and VSSQ pins must be on the same level.
 3. VIH (max.) = VDD + 1.5V (pulse width ≤ 5ns).
 4. VIL (min.) = VSS - 1.5V (pulse width ≤ 5ns).

DC Characteristics 1 (TA = 0°C to +70°C, VDD, VDDQ = 3.3V ± 0.3V, VSS, VSSQ = 0V) [EDS6432AF]
 (TA = 0°C to +70°C, VDD, VDDQ = 2.5V ± 0.2V, VSS, VSSQ = 0V) [EDS6432CF]

| Parameter | Symbol | Grade | EDS6432AF | | EDS6432CF | | Unit | Test condition | Notes |
|--|--------|------------|------------|------------|-----------|------|------|--------------------------------------|---------|
| | | | max. | max. | max. | max. | | | |
| Operating current | IDD1 | -6B -75 | 120 100 | 120 100 | | | mA | Burst length = 1 tRC = tRC (min.) | 1, 2, 3 |
| Standby current in power down | IDD2P | | 3 | 3 | | | mA | CKE = VIL, tCK = tCK (min.) | 6 |
| Standby current in power down (input signal stable) | IDD2PS | | 2 | 2 | | | mA | CKE = VIL, tCK = ∞ | 7 |
| Standby current in non power down | IDD2N | | 20 | 20 | | | mA | CKE, /CS = VIH, tCK = tCK (min.) | 4 |
| Standby current in non power down (input signal stable) | IDD2NS | | 9 | 9 | | | mA | CKE = VIH, tCK = ∞, /CS = VIH | 8 |
| Active standby current in power down | IDD3P | | 4 | 4 | | | mA | CKE = VIL, tCK = tCK (min.) | 1, 2, 6 |
| Active standby current in power down (input signal stable) | IDD3PS | | 3 | 3 | | | mA | CKE = VIL, tCK = ∞ | 2, 7 |
| Active standby current in non power down | IDD3N | | 40 | 40 | | | mA | CKE, /CS = VIH, tCK = tCK (min.) | 1, 2, 4 |
| Active standby current in non power down (input signal stable) | IDD3NS | | 30 | 30 | | | mA | CKE = VIH, tCK = ∞, /CS = VIH | 2, 8 |
| Burst operating current | IDD4 | -6B -75 | 150 130 | 150 130 | | | mA | tCK = tCK (min.), BL = 4 | 1, 2, 5 |
| Refresh current | IDD5 | -6B -75 | 260 220 | 260 220 | | | mA | tRC = tRC (min.) | 3 |
| Self refresh current | IDD6 | | 1.5 | 1.5 | | | mA | VIH ≥ VDD – 0.2V VIL ≤ 0.2V | |

Notes: 1. IDD depends on output load condition when the device is selected. IDD (max.) is specified at the output open condition.

2. One bank operation.
3. Input signals are changed once per one clock.
4. Input signals are changed once per two clocks.
5. Input signals are changed once per four clocks.
6. After power down mode, CLK operating current.
7. After power down mode, no CLK operating current.
8. Input signals are VIH or VIL fixed.

**DC Characteristics 2 (TA = 0°C to +70°C, VDD, VDDQ = 3.3V ± 0.3V, VSS, VSSQ = 0V) [EDS6432AF]
(TA = 0°C to +70°C, VDD, VDDQ = 2.5V ± 0.2V, VSS, VSSQ = 0V) [EDS6432CF]**

[EDS6432AF]

| Parameter | Symbol | min. | max. | Unit | Test condition | Note |
|------------------------|--------|------|------|------|------------------------------|------|
| Input leakage current | ILI | -1 | 1 | μA | 0 ≤ VIN ≤ VDD | |
| Output leakage current | ILO | -1.5 | 1.5 | μA | 0 ≤ VOUT ≤ VDD, DQ = disable | |
| Output high voltage | VOH | 2.4 | — | V | IOH = -2 mA | |
| Output low voltage | VOL | — | 0.4 | V | IOL = 2 mA | |

[EDS6432CF]

| Parameter | Symbol | min. | max. | Unit | Test condition | Note |
|------------------------|--------|------|------|------|------------------------------|------|
| Input leakage current | ILI | -1 | 1 | μA | 0 ≤ VIN ≤ VDD | |
| Output leakage current | ILO | -1.5 | 1.5 | μA | 0 ≤ VOUT ≤ VDD, DQ = disable | |
| Output high voltage | VOH | 2.0 | — | V | IOH = -1 mA | |
| Output low voltage | VOL | — | 0.4 | V | IOL = 1 mA | |

**Pin Capacitance (TA = 25°C, VDD, VDDQ = 3.3V ± 0.3V) [EDS6432AF]
(TA = 25°C, VDD, VDDQ = 2.5V ± 0.2V) [EDS6432CF]**

| Parameter | Symbol | Pins | min. | typ. | max. | Unit | Notes |
|-------------------------------|--------|---|------|------|------|------|------------|
| Input capacitance | C11 | CLK | 1.5 | — | 3.5 | pF | 1, 2, 4 |
| | C12 | Address, CKE, /CS, /RAS, /CAS, /WE, DQM | 1.5 | — | 3.8 | pF | 1, 2, 4 |
| Data input/output capacitance | C1/O | DQ | 3.0 | — | 6.5 | pF | 1, 2, 3, 4 |

- Notes: 1. Capacitance measured with Boonton Meter or effective capacitance measuring method.
 2. Measurement condition: f = 1MHz, 1.4V(EDS6432AFBH) and 1.2V (EDS6432CFBH) bias, 200mV swing.
 3. DQM = VIH to disable DOUT.
 4. This parameter is sampled and not 100% tested.

AC Characteristics (TA = 0°C to +70°C, VDD, VDDQ = 3.3V ± 0.3V, VSS, VSSQ = 0V) [EDS6432AF]
(TA = 0°C to +70°C, VDD, VDDQ = 2.5V ± 0.2V, VSS, VSSQ = 0V) [EDS6432CF]

| Parameter | Symbol | -6B | | -75 | | Unit | Notes |
|---|--------|----------------|--------|----------------|--------|------|---------|
| | | min. | max. | min. | max. | | |
| System clock cycle time (CL = 2) | tCK | 10 | — | 10 | — | ns | 1 |
| (CL = 3) | tCK | 6 | — | 7.5 | — | ns | 1 |
| CLK high pulse width | tCH | 2.5 | — | 2.5 | — | ns | 1 |
| CLK low pulse width | tCL | 2.5 | — | 2.5 | — | ns | 1 |
| Access time from CLK | tAC | — | 5.4 | — | 5.4 | ns | 1, 2 |
| Data-out hold time | tOH | 2 | — | 2 | — | ns | 1, 2 |
| CLK to Data-out low impedance | tLZ | 0 | — | 0 | — | ns | 1, 2, 3 |
| CLK to Data-out high impedance | tHZ | — | 5.4 | — | 5.4 | ns | 1, 4 |
| Input setup time | tSI | 1.5 | — | 1.5 | — | ns | 1 |
| Input hold time | tHI | 0.8 | — | 0.8 | — | ns | 1 |
| Ref/Active to Ref/Active command period | tRC | 60 | — | 67.5 | — | ns | 1 |
| Active to Precharge command period | tRAS | 42 | 120000 | 45 | 120000 | ns | 1 |
| Active command to column command (same bank) | tRCD | 18 | — | 20 | — | ns | 1 |
| Precharge to active command period | tRP | 18 | — | 20 | — | ns | 1 |
| Write recovery or data-in to precharge lead time | tDPL | 12 | — | 15 | — | ns | 1 |
| Last data into active latency | tDAL | 2CLK + 18ns | — | 2CLK + 20ns | — | | |
| Active (a) to Active (b) command period | tRRD | 12 | — | 15 | — | ns | 1 |
| Transition time (rise and fall) | tT | 0.5 | 5 | 0.5 | 5 | ns | |
| Refresh period (4096 refresh cycles) | tREF | — | 64 | — | 64 | ms | |

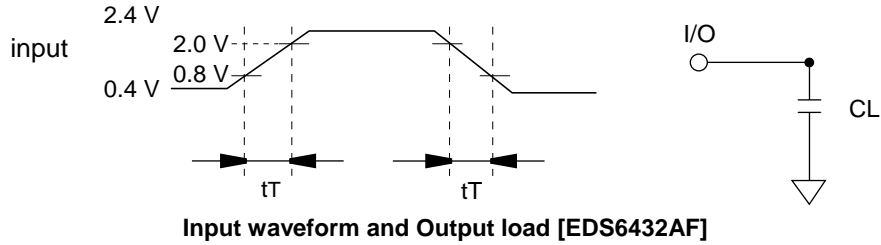
Notes: 1. AC measurement assumes tT = 0.5ns. Reference level for timing of input signals is 1.4V(EDS6432AF) and 1.2V (EDS6432CF).

2. Access time is measured at 1.4V(EDS6432AF) and 1.2V (EDS6432CF). Load condition is CL = 30pF.
3. tLZ (min.) defines the time at which the outputs achieves the low impedance state.
4. tHZ (max.) defines the time at which the outputs achieves the high impedance state.

Test Conditions

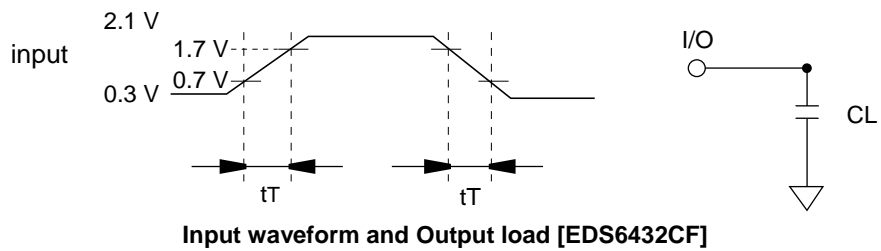
[EDS6432AF]

- AC high level voltage/low level input voltage: 2.4V/0.4V
- Input and output timing reference levels: 1.4V
- Output timing measurement reference level: 1.4V
- Input waveform and output load: See following figures



[EDS6432CF]

- AC high level voltage/low level input voltage: 2.1V/0.3V
- Input and output timing reference levels: 1.2V
- Output timing measurement reference level: 1.2V
- Input waveform and output load: See following figures



Relationship Between Frequency and Minimum Latency

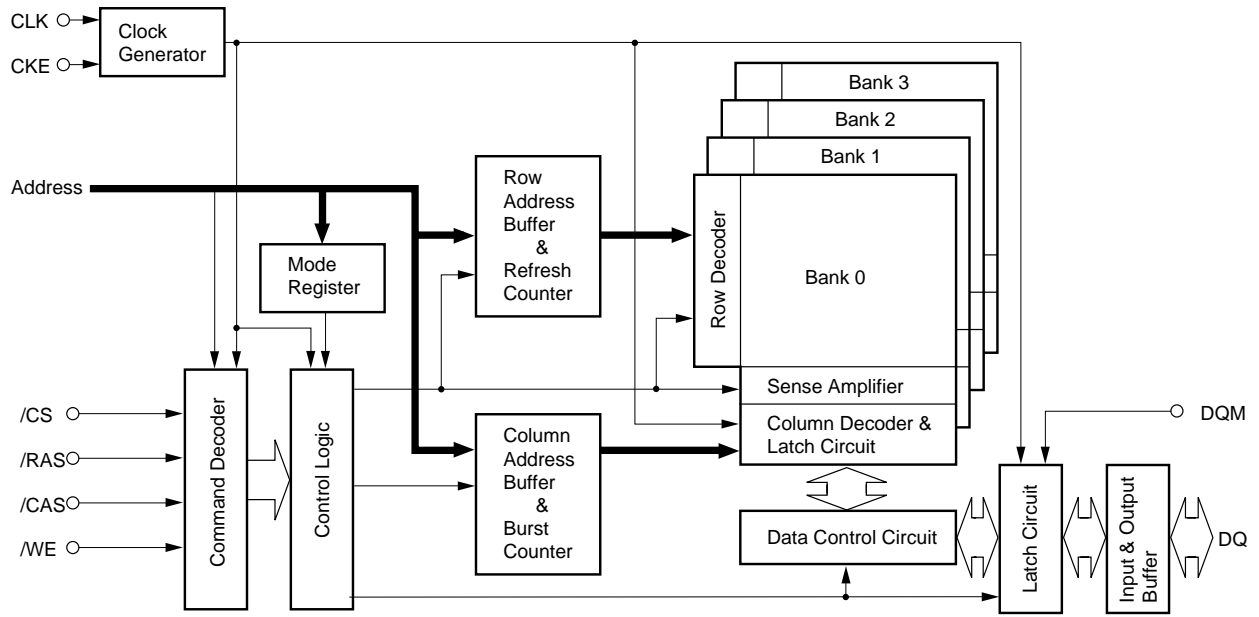
| Parameter | Symbol | -6B | | -75 | | Unit | Notes |
|---|--------|-----|-----|-----|-----|------|----------------------|
| | | 166 | 100 | 133 | 100 | | |
| tCK (ns) | Symbol | 6 | 10 | 7.5 | 10 | tCK | |
| Active command to column command (same bank) | /RCD | 3 | 2 | 3 | 2 | tCK | 1 |
| Active command to active command (same bank) | /RC | 10 | 7 | 9 | 7 | tCK | 1 |
| Active command to precharge command (same bank) | /RAS | 7 | 5 | 6 | 5 | tCK | 1 |
| Precharge command to active command (same bank) | /RP | 3 | 2 | 3 | 2 | tCK | 1 |
| Write recovery or data-in to precharge command (same bank) | /DPL | 2 | 2 | 2 | 2 | tCK | 1 |
| Active command to active command (different bank) | /RRD | 2 | 2 | 2 | 2 | tCK | 1 |
| Self refresh exit time | /SREX | 1 | 1 | 1 | 1 | tCK | 2 |
| Last data in to active command (Auto precharge, same bank) | /DAL | 5 | 4 | 5 | 4 | tCK | = [DPL + /RP] |
| Self refresh exit to command input | /SEC | 10 | 7 | 9 | 7 | tCK | = [$\frac{RC}{3}$] |
| Precharge command to high impedance (CL = 2) | /HZP | — | 2 | — | 2 | tCK | |
| (CL = 3) | /HZP | 3 | 3 | 3 | 3 | tCK | |
| Last data out to active command (Auto precharge, same bank) | /APR | 1 | 1 | 1 | 1 | tCK | |
| Last data out to precharge (early precharge) (CL = 2) | /EP | — | -1 | — | -1 | tCK | |
| (CL = 3) | /EP | -2 | -2 | -2 | -2 | tCK | |
| Column command to column command | /CCD | 1 | 1 | 1 | 1 | tCK | |
| Write command to data in latency | /WCD | 0 | 0 | 0 | 0 | tCK | |
| DQM to data in | /DID | 0 | 0 | 0 | 0 | tCK | |
| DQM to data out | /DOD | 2 | 2 | 2 | 2 | tCK | |
| CKE to CLK disable | /CLE | 1 | 1 | 1 | 1 | tCK | |
| Register set to active command | /MRD | 2 | 2 | 2 | 2 | tCK | |
| /CS to command disable | /CDD | 0 | 0 | 0 | 0 | tCK | |
| Power down exit to command input | /PEC | 1 | 1 | 1 | 1 | tCK | |

Notes: 1. /RCD to /RRD are recommended value.

2. Be valid [DESL] or [NOP] at next command of self refresh exit.

3. Except [DESL] and [NOP]

Block Diagram



Pin Function

CLK (input pin)

CLK is the master clock input. Other inputs signals are referenced to the CLK rising edge.

CKE (input pins)

CKE determine validity of the next CLK (clock). If CKE is high, the next CLK rising edge is valid; otherwise it is invalid. If the CLK rising edge is invalid, the internal clock is not issued and the Synchronous DRAM suspends operation.

When the Synchronous DRAM is not in burst mode and CKE is negated, the device enters power down mode. During power down mode, CKE must remain low.

/CS (input pins)

/CS low starts the command input cycle. When /CS is high, commands are ignored but operations continue.

/RAS, /CAS, and /WE (input pins)

/RAS, /CAS and /WE have the same symbols on conventional DRAM but different functions. For details, refer to the command table.

A0 to A10 (input pins)

Row Address is determined by A0 to A10 at the CLK (clock) rising edge in the active command cycle.

Column Address is determined by A0 to A7 at the CLK rising edge in the read or write command cycle.

A10 defines the precharge mode. When A10 is high in the precharge command cycle, all banks are precharged; when A10 is low, only the bank selected by BA0 and BA1 is precharged.

When A10 is high in read or write command cycle, the precharge starts automatically after the burst access.

BA0 and BA1 (input pin)

BA0 and BA1 are bank select signal (BS). (See Bank Select Signal Table)

[Bank Select Signal Table]

| | BA0 | BA1 |
|--------|-----|-----|
| Bank 0 | L | L |
| Bank 1 | H | L |
| Bank 2 | L | H |
| Bank 3 | H | H |

Remark: H: VIH. L: VIL.

DQM (input pins)

DQM controls I/O buffers. DQM0 controls DQ0 to DQ7, DQM1 controls DQ8 to DQ15, DQM2 controls DQ16 to DQ23, DQM3 controls DQ24 to DQ31. In read mode, DQM controls the output buffers like a conventional /OE pin. DQM high and DQM low turn the output buffers off and on, respectively. The DQM latency for the read is two clocks. In write mode, DQM controls the word mask. Input data is written to the memory cell if DQM is low but not if DQM is high. The DQM latency for the write is zero.

DQ0 to DQ31 (input/output pins)

DQ pins have the same function as I/O pins on a conventional DRAM.

VDD, VSS, VDDQ, VSSQ (Power supply)

VDD and VSS are power supply pins for internal circuits. VDDQ and VSSQ are power supply pins for the output buffers.

Command Operation

Command Truth Table

The SDRAM recognizes the following commands specified by the /CS, /RAS, /CAS, /WE and address pins.

| Function | Symbol | CKE | | /CS | /RAS | /CAS | /WE | BA1 | BA0 | A10 | A0 to A10 |
|---------------------------|--------|-------|---|-----|------|------|-----|-----|-----|-----|--------------|
| | | n - 1 | n | | | | | | | | |
| Device deselect | DESL | H | × | H | × | × | × | × | × | × | × |
| No operation | NOP | H | × | L | H | H | H | × | × | × | × |
| Burst stop | BST | H | × | L | H | H | L | × | × | × | × |
| Read | READ | H | × | L | H | L | H | V | V | L | V |
| Read with auto precharge | READA | H | × | L | H | L | H | V | V | H | V |
| Write | WRIT | H | × | L | H | L | L | V | V | L | V |
| Write with auto precharge | WRITA | H | × | L | H | L | L | V | V | H | V |
| Bank activate | ACT | H | × | L | L | H | H | V | V | V | V |
| Precharge select bank | PRE | H | × | L | L | H | L | V | V | L | × |
| Precharge all banks | PALL | H | × | L | L | H | L | × | × | H | × |
| Mode register set | MRS | H | × | L | L | L | L | L | L | L | V |

Remark: H: VIH. L: VIL. ×: VIH or VIL. V: Valid address input.

Device deselect command [DESL]

When this command is set (/CS is High), the SDRAM ignore command input at the clock. However, the internal status is held.

No operation [NOP]

This command is not an execution command. However, the internal operations continue.

Burst stop command [BST]

This command can stop the current burst operation.

Column address strobe and read command [READ]

This command starts a read operation. In addition, the start address of burst read is determined by the column address (see Address Pins Table in Pin Function) and the bank select address (BA0, BA1). After the read operation, the output buffer becomes High-Z.

Read with auto-precharge [READA]

This command automatically performs a precharge operation after a burst read with a burst length of 1, 2, 4 or 8.

Column address strobe and write command [WRIT]

This command starts a write operation. When the burst write mode is selected, the column address (see Address Pins Table in Pin Function) and the bank select address (BA0, BA1) become the burst write start address. When the single write mode is selected, data is only written to the location specified by the column address (see Address Pins Table in Pin Function) and the bank select address (BA0, BA1).

Write with auto-precharge [WRITA]

This command automatically performs a precharge operation after a burst write with a length of 1, 2, 4 or 8, or after a single write operation.

Row address strobe and bank activate [ACT]

This command activates the bank that is selected by BA0, BA1 and determines the row address (A0 to A10). (See Bank Select Signal Table)

Precharge selected bank [PRE]

This command starts precharge operation for the bank selected by BA0, BA1. (See Bank Select Signal Table)

[Bank Select Signal Table]

| | BA0 | BA1 |
|--------|-----|-----|
| Bank 0 | L | L |
| Bank 1 | H | L |
| Bank 2 | L | H |
| Bank 3 | H | H |

Remark: H: VIH. L: VIL.

Precharge all banks [PALL]

This command starts a precharge operation for all banks.

Refresh [REF/SELF]

This command starts the refresh operation. There are two types of refresh operation, the one is auto-refresh, and the other is self-refresh. For details, refer to the CKE truth table section.

Mode register set [MRS]

The SDRAM has a mode register that defines how it operates. The mode register is specified by the address pins (A0 to BA0 and BA1) at the mode register set cycle. For details, refer to the Mode Register Configuration. After power on, the contents of the mode register are undefined, execute the mode register set command to set up the mode register.

DQM Truth Table

| Function | Symbol | CKE | | DQM | | | |
|---|--------|-------|---|-----|---|---|---|
| | | n – 1 | n | 0 | 1 | 2 | 3 |
| Data write / output enable | ENB | H | × | L | L | L | L |
| Data mask / output disable | MASK | H | × | H | H | H | H |
| DQ0 to DQ7 write enable/output enable | ENB0 | H | × | L | × | × | × |
| DQ8 to DQ15 write enable/output enable | ENB1 | H | × | × | L | × | × |
| DQ16 to DQ23 write enable/output enable | ENB2 | H | × | × | × | L | × |
| DQ24 to DQ31 write enable/output enable | ENB3 | H | × | × | × | × | L |
| DQ0 to DQ7 write inhibit/output disable | MASK0 | H | × | H | × | × | × |
| DQ8 to DQ15 write inhibit/output disable | MASK 1 | H | × | × | H | × | × |
| DQ16 to DQ23 write inhibit/output disable | MASK 2 | H | × | × | × | H | × |
| DQ24 to DQ31 write inhibit/output disable | MASK 3 | H | × | × | × | × | H |

Remark: H: VIH. L: VIL. ×: VIH or VIL
 Write: /DID is needed.
 Read: /DOD is needed.

CKE Truth Table

| Current state | Function | Symbol | CKE | | | | | | | |
|---------------|----------------------------|--------|-------|---|-----|------|------|-----|---------|--|
| | | | n – 1 | n | /CS | /RAS | /CAS | /WE | Address | |
| Activating | Clock suspend mode entry | | H | L | × | × | × | × | × | |
| Any | Clock suspend mode | | L | L | × | × | × | × | × | |
| Clock suspend | Clock suspend mode exit | | L | H | × | × | × | × | × | |
| Idle | CBR (auto) refresh command | REF | H | H | L | L | L | H | × | |
| Idle | Self refresh entry | SELF | H | L | L | L | L | H | × | |
| Self refresh | Self refresh exit | | L | H | L | H | H | H | × | |
| | | | L | H | H | × | × | × | × | |
| Idle | Power down entry | | H | L | L | H | H | H | × | |
| | | | H | L | H | × | × | × | × | |
| Power down | Power down exit | | L | H | H | × | × | × | × | |
| | | | L | H | L | H | H | H | × | |

Remark: H: VIH. L: VIL. ×: VIH or VIL

Function Truth Table

The following table shows the operations that are performed when each command is issued in each mode of the SDRAM.

The following table assumes that CKE is high.

| Current state | /CS | /RAS | /CAS | /WE | Address | Command | Operation |
|---------------|-----|------|------|-----|-------------|------------|---|
| Precharge | H | × | × | × | × | DESL | Enter IDLE after tRP |
| | L | H | H | H | × | NOP | Enter IDLE after tRP |
| | L | H | H | L | × | BST | ILLEGAL |
| | L | H | L | H | BA, CA, A10 | READ/READA | ILLEGAL* ³ |
| | L | H | L | L | BA, CA, A10 | WRIT/WRITA | ILLEGAL* ³ |
| | L | L | H | H | BA, RA | ACT | ILLEGAL* ³ |
| | L | L | H | L | BA, A10 | PRE, PALL | NOP* ⁵ |
| | L | L | L | H | × | REF, SELF | ILLEGAL |
| | L | L | L | L | MODE | MRS | ILLEGAL |
| Idle | H | × | × | × | × | DESL | NOP |
| | L | H | H | H | × | NOP | NOP |
| | L | H | H | L | × | BST | ILLEGAL |
| | L | H | L | H | BA, CA, A10 | READ/READA | ILLEGAL* ⁴ |
| | L | H | L | L | BA, CA, A10 | WRIT/WRITA | ILLEGAL* ⁴ |
| | L | L | H | H | BA, RA | ACT | Bank and row active |
| | L | L | H | L | BA, A10 | PRE, PALL | NOP |
| | L | L | L | H | × | REF, SELF | Refresh |
| | L | L | L | L | MODE | MRS | Mode register set* ⁸ |
| Row active | H | × | × | × | × | DESL | NOP |
| | L | H | H | H | × | NOP | NOP |
| | L | H | H | L | × | BST | ILLEGAL |
| | L | H | L | H | BA, CA, A10 | READ/READA | Begin read* ⁶ |
| | L | H | L | L | BA, CA, A10 | WRIT/WRITA | Begin write* ⁶ |
| | L | L | H | H | BA, RA | ACT | Other bank active ILLEGAL on same bank* ² |
| | L | L | H | L | BA, A10 | PRE, PALL | Precharge* ⁷ |
| | L | L | L | H | × | REF, SELF | ILLEGAL |
| | L | L | L | L | MODE | MRS | ILLEGAL |
| Read | H | × | × | × | × | DESL | Continue burst to end |
| | L | H | H | H | × | NOP | Continue burst to end |
| | L | H | H | L | × | BST | Burst stop |
| | L | H | L | H | BA, CA, A10 | READ/READA | Continue burst read to /CAS latency and New read |
| | L | H | L | L | BA, CA, A10 | WRIT/WRITA | Term burst read/start write |
| | L | L | H | H | BA, RA | ACT | Other bank active ILLEGAL on same bank* ² |
| | L | L | H | L | BA, A10 | PRE, PALL | Term burst read and Precharge |
| | L | L | L | H | × | REF, SELF | ILLEGAL |
| | L | L | L | L | MODE | MRS | ILLEGAL |

| Current state | /CS | /RAS | /CAS | /WE | Address | Command | Operation |
|---------------------------|-----|------|------|-----|-------------|------------|---|
| Read with auto-precharge | H | × | × | × | × | DESL | Continue burst to end and precharge |
| | L | H | H | H | × | NOP | Continue burst to end and precharge |
| | L | H | H | L | × | BST | ILLEGAL |
| | L | H | L | H | BA, CA, A10 | READ/READA | ILLEGAL ^{*3} |
| | L | H | L | L | BA, CA, A10 | WRIT/WRITA | ILLEGAL ^{*3} |
| | L | L | H | H | BA, RA | ACT | Other bank active ILLEGAL on same bank ^{*2} |
| | L | L | H | L | BA, A10 | PRE, PALL | ILLEGAL ^{*3} |
| | L | L | L | H | × | REF, SELF | ILLEGAL |
| | L | L | L | L | MODE | MRS | ILLEGAL |
| Write | H | × | × | × | × | DESL | Continue burst to end |
| | L | H | H | H | × | NOP | Continue burst to end |
| | L | H | H | L | × | BST | Burst stop |
| | L | H | L | H | BA, CA, A10 | READ/READA | Term burst and New read |
| | L | H | L | L | BA, CA, A10 | WRIT/WRITA | Term burst and New write |
| | L | L | H | H | BA, RA | ACT | Other bank active ILLEGAL on same bank ^{*3} |
| | L | L | H | L | BA, A10 | PRE, PALL | Term burst write and Precharge ^{*1} |
| | L | L | L | H | × | REF, SELF | ILLEGAL |
| | L | L | L | L | MODE | MRS | ILLEGAL |
| Write with auto-precharge | H | × | × | × | × | DESL | Continue burst to end and precharge |
| | L | H | H | H | × | NOP | Continue burst to end and precharge |
| | L | H | H | L | × | BST | ILLEGAL |
| | L | H | L | H | BA, CA, A10 | READ/READA | ILLEGAL ^{*3} |
| | L | H | L | L | BA, CA, A10 | WRIT/WRITA | ILLEGAL ^{*3} |
| | L | L | H | H | BA, RA | ACT | Other bank active ILLEGAL on same bank ^{*3} |
| | L | L | H | L | BA, A10 | PRE, PALL | ILLEGAL ^{*3} |
| | L | L | L | H | × | REF, SELF | ILLEGAL |
| | L | L | L | L | MODE | MRS | ILLEGAL |
| Refresh (auto-refresh) | H | × | × | × | × | DESL | Enter IDLE after tRC |
| | L | H | H | H | × | NOP | Enter IDLE after tRC |
| | L | H | H | L | × | BST | ILLEGAL |
| | L | H | L | H | BA, CA, A10 | READ/READA | ILLEGAL ^{*4} |
| | L | H | L | L | BA, CA, A10 | WRIT/WRITA | ILLEGAL ^{*4} |
| | L | L | H | H | BA, RA | ACT | ILLEGAL ^{*4} |
| | L | L | H | L | BA, A10 | PRE, PALL | ILLEGAL ^{*4} |
| | L | L | L | H | × | REF, SELF | ILLEGAL |
| | L | L | L | L | MODE | MRS | ILLEGAL |

| Current state | /CS | /RAS | /CAS | /WE | Address | Command | Operation |
|-------------------|-----|------|------|-----|-------------|------------|-----------------------------------|
| Mode register set | H | × | × | × | × | DESL | NOP |
| | L | H | H | H | × | NOP | NOP |
| | L | H | H | L | × | BST | ILLEGAL |
| | L | H | L | H | BA, CA, A10 | READ/READA | ILLEGAL ^{*4} |
| | L | H | L | L | BA, CA, A10 | WRIT/WRITA | ILLEGAL ^{*4} |
| | L | L | H | H | BA, RA | ACT | Bank and row active ^{*9} |
| | L | L | H | L | BA, A10 | PRE, PALL | NOP |
| | L | L | L | H | × | REF, SELF | Refresh ^{*9} |
| | L | L | L | L | MODE | MRS | Mode register set ^{†*8} |

Remark: H: VIH. L: VIL. ×: VIH or VIL

Notes: 1. An interval of tDPL is required between the final valid data input and the precharge command.

2. If tRRD is not satisfied, this operation is illegal.
3. Illegal for same bank, except for another bank.
4. Illegal for all banks.
5. NOP for same bank, except for another bank.
6. Illegal if tRCD is not satisfied.
7. Illegal if tRAS is not satisfied.
8. MRS command must be issued after DOUT finished, in case of DOUT remaining.
9. Illegal if /MRD is not satisfied.

Command Truth Table for CKE

| Current State | CKE | | | | | | | Operation | Notes |
|-----------------------------------|------------|---|-----|------|------|-----|---------|--|---|
| | n – 1 | n | /CS | /RAS | /CAS | /WE | Address | | |
| Self refresh | H | x | x | x | x | x | x | INVALID, CLK (n – 1) would exit self refresh | |
| | L | H | H | x | x | x | x | Self refresh recovery | |
| | L | H | L | H | H | x | x | Self refresh recovery | |
| | L | H | L | H | L | x | x | ILLEGAL | |
| | L | H | L | L | x | x | x | ILLEGAL | |
| | L | L | x | x | x | x | x | Continue self refresh | |
| Self refresh recovery | H | H | H | x | x | x | x | Idle after t _{RC} | |
| | H | H | L | H | H | x | x | Idle after t _{RC} | |
| | H | H | L | H | L | x | x | ILLEGAL | |
| | H | H | L | L | x | x | x | ILLEGAL | |
| | H | L | H | x | x | x | x | ILLEGAL | |
| | H | L | L | H | H | x | x | ILLEGAL | |
| | H | L | L | H | L | x | x | ILLEGAL | |
| | H | L | L | L | x | x | x | ILLEGAL | |
| Power down | H | x | x | x | x | x | | INVALID, CLK (n – 1) would exit power down | |
| | L | H | H | x | x | x | x | EXIT power down | |
| | L | H | L | H | H | H | x | EXIT power down | |
| | L | L | x | x | x | x | x | Continue power down mode | |
| All banks idle | H | H | H | x | x | x | | Refer to operations in Function Truth Table | |
| | H | H | L | H | x | x | | Refer to operations in Function Truth Table | |
| | H | H | L | L | H | x | | Refer to operations in Function Truth Table | |
| | H | H | L | L | L | H | x | CBR (auto) Refresh | |
| | H | H | L | L | L | L | OPCODE | Refer to operations in Function Truth Table | |
| | H | L | H | x | x | x | | Begin power down next cycle | |
| | H | L | L | H | x | x | | Refer to operations in Function Truth Table | |
| | H | L | L | L | H | x | | Refer to operations in Function Truth Table | |
| | H | L | L | L | L | H | x | Self refresh | 1 |
| | H | L | L | L | L | L | OPCODE | Refer to operations in Function Truth Table | |
| | L | H | x | x | x | x | x | Exit power down next cycle | |
| | L | L | x | x | x | x | x | Power down | 1 |
| | Row active | H | x | x | x | x | x | x | Refer to operations in Function Truth Table |
| L | | x | x | x | x | x | x | Clock suspend | 1 |
| Any state other than listed above | H | H | x | x | x | x | | Refer to operations in Function Truth Table | |
| | H | L | x | x | x | x | x | Begin clock suspend next cycle | 2 |
| | L | H | x | x | x | x | x | Exit clock suspend next cycle | |
| | L | L | x | x | x | x | x | Maintain clock suspend | |

Remark: H: VIH. L: VIL. x: VIH or VIL

Notes: 1. Self refresh can be entered only from the all banks idle state. Power down can be entered only from all banks idle. Clock suspend can be entered only from following states, row active, read, read with auto-precharge, write and write with auto precharge.

2. Must be legal command as defined in Function Truth Table.

Clock suspend mode entry

The SDRAM enters clock suspend mode from active mode by setting CKE to Low. If command is input in the clock suspend mode entry cycle, the command is valid. The clock suspend mode changes depending on the current status (1 clock before) as shown below.

ACTIVE clock suspend

This suspend mode ignores inputs after the next clock by internally maintaining the bank active status.

READ suspend and READ with Auto-precharge suspend

The data being output is held (and continues to be output).

WRITE suspend and WRIT with Auto-precharge suspend

In this mode, external signals are not accepted. However, the internal state is held.

Clock suspend

During clock suspend mode, keep the CKE to Low.

Clock suspend mode exit

The SDRAM exits from clock suspend mode by setting CKE to High during the clock suspend state.

IDLE

In this state, all banks are not selected, and completed precharge operation.

Auto-refresh command [REF]

When this command is input from the IDLE state, the SDRAM starts auto-refresh operation. (The auto-refresh is the same as the CBR refresh of conventional DRAMs.) During the auto-refresh operation, refresh address and bank select address are generated inside the SDRAM. For every auto-refresh cycle, the internal address counter is updated. Accordingly, 4096 times are required to refresh the entire memory. Before executing the auto-refresh command, all the banks must be in the IDLE state. In addition, since the precharge for all banks is automatically performed after auto-refresh, no precharge command is required after auto-refresh.

Self-refresh entry [SELF]

When this command is input during the IDLE state, the SDRAM starts self-refresh operation. After the execution of this command, self-refresh continues while CKE is Low. Since self-refresh is performed internally and automatically, external refresh operations are unnecessary.

Power down mode entry

When this command is executed during the IDLE state, the SDRAM enters power down mode. In power down mode, power consumption is suppressed by cutting off the initial input circuit.

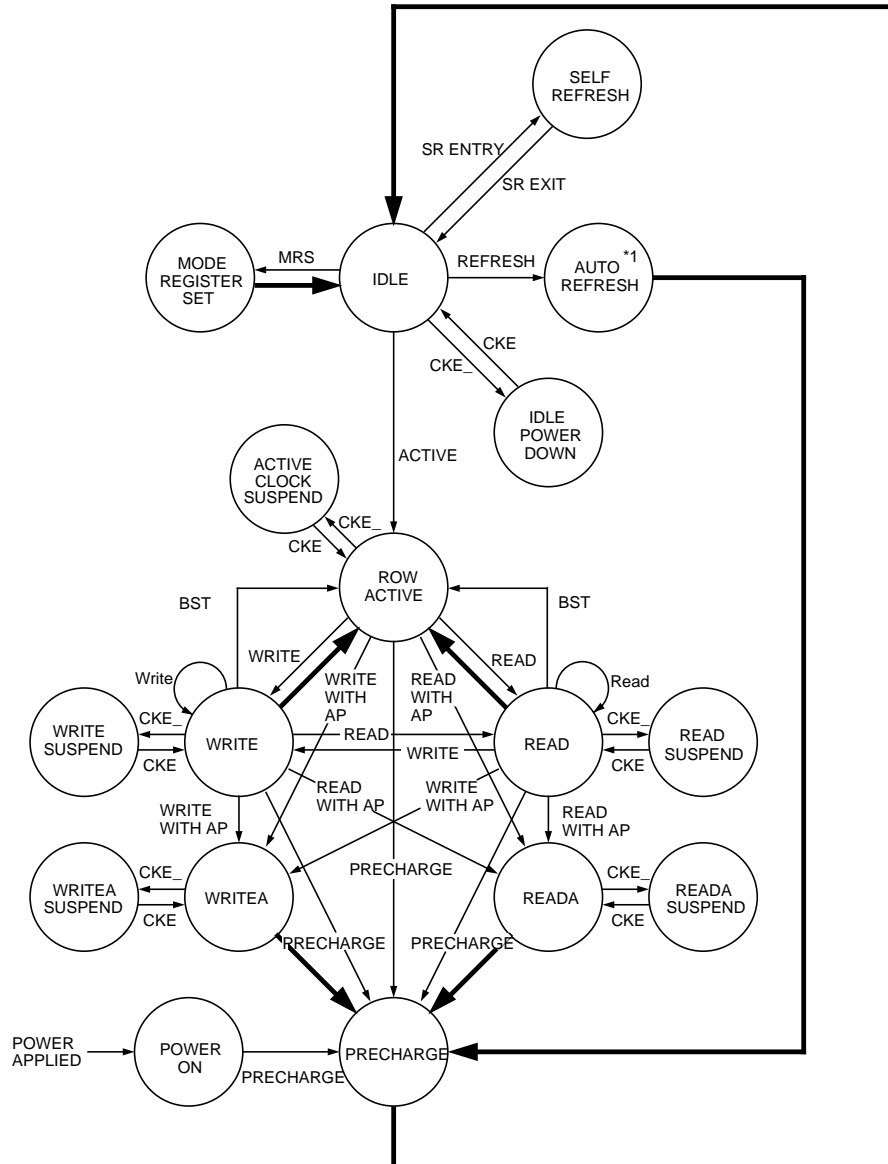
Self-refresh exit

When this command is executed during self-refresh mode, the SDRAM can exit from self-refresh mode. After exiting from self-refresh mode, the SDRAM enters the IDLE state.

Power down exit

When this command is executed at the power down mode, the SDRAM can exit from power down mode. After exiting from power down mode, the SDRAM enters the IDLE state.

Simplified State Diagram



➡ Automatic transition after completion of command.
 → Transition resulting from command input.

Note: 1. After the auto-refresh operation, precharge operation is performed automatically and enter the IDLE state.

Mode Register Configuration

Mode Register Set

The mode register is set by the input to the address pins (A0 to A10, BA0 and BA1) during mode register set cycles. The mode register consists of five sections, each of which is assigned to address pins.

BA1, BA0, A8, A9, A10: (OPCODE): The SDRAM has two types of write modes. One is the burst write mode, and the other is the single write mode. These bits specify write mode.

Burst read and burst write: Burst write is performed for the specified burst length starting from the column address specified in the write cycle.

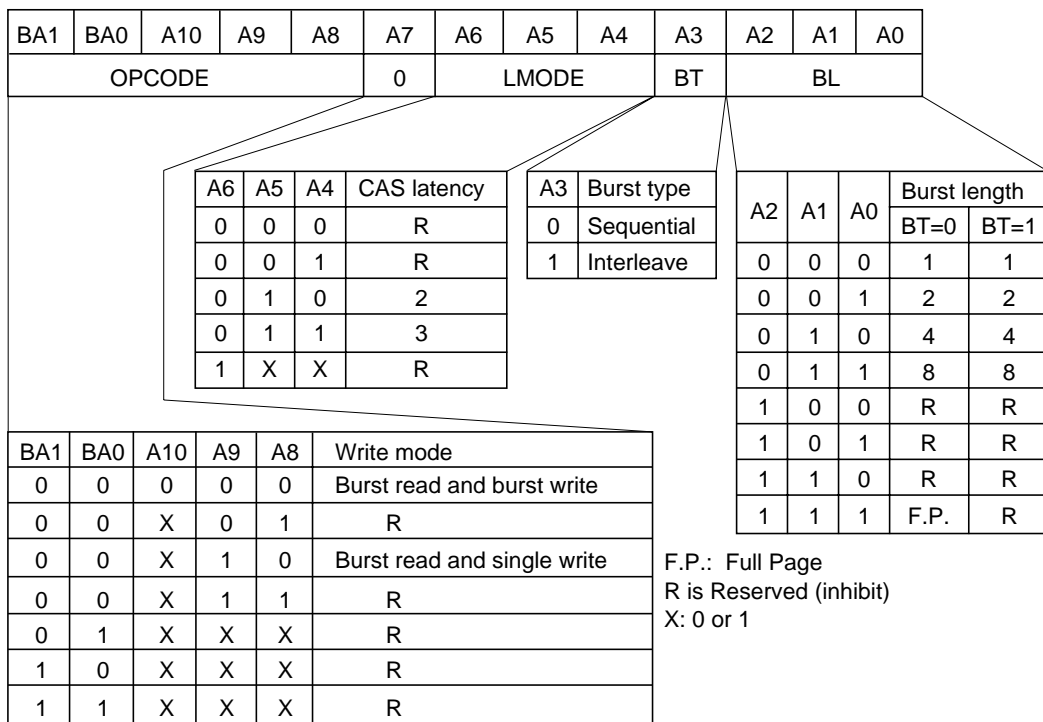
Burst read and single write: Data is only written to the column address specified during the write cycle, regardless of the burst length.

A7: Keep this bit Low at the mode register set cycle. If this pin is high, the vender test mode is set.

A6, A5, A4: (LMODE): These pins specify the /CAS latency.

A3: (BT): A burst type is specified.

A2, A1, A0: (BL): These pins specify the burst length.



Mode Register Set

Burst length = 2

| Starting Ad. | Addressing(decimal) | |
|--------------|---------------------|------------|
| A0 | Sequential | Interleave |
| 0 | 0, 1, | 0, 1, |
| 1 | 1, 0, | 1, 0, |

Burst length = 4

| Starting Ad. | | Addressing(decimal) | |
|--------------|----|---------------------|-------------|
| A1 | A0 | Sequential | Interleave |
| 0 | 0 | 0, 1, 2, 3, | 0, 1, 2, 3, |
| 0 | 1 | 1, 2, 3, 0, | 1, 0, 3, 2, |
| 1 | 0 | 2, 3, 0, 1, | 2, 3, 0, 1, |
| 1 | 1 | 3, 0, 1, 2, | 3, 2, 1, 0, |

Burst length = 8

| Starting Ad. | | | Addressing(decimal) | |
|--------------|----|----|-------------------------|-------------------------|
| A2 | A1 | A0 | Sequential | Interleave |
| 0 | 0 | 0 | 0, 1, 2, 3, 4, 5, 6, 7, | 0, 1, 2, 3, 4, 5, 6, 7, |
| 0 | 0 | 1 | 1, 2, 3, 4, 5, 6, 7, 0, | 1, 0, 3, 2, 5, 4, 7, 6, |
| 0 | 1 | 0 | 2, 3, 4, 5, 6, 7, 0, 1, | 2, 3, 0, 1, 6, 7, 4, 5, |
| 0 | 1 | 1 | 3, 4, 5, 6, 7, 0, 1, 2, | 3, 2, 1, 0, 7, 6, 5, 4, |
| 1 | 0 | 0 | 4, 5, 6, 7, 0, 1, 2, 3, | 4, 5, 6, 7, 0, 1, 2, 3, |
| 1 | 0 | 1 | 5, 6, 7, 0, 1, 2, 3, 4, | 5, 4, 7, 6, 1, 0, 3, 2, |
| 1 | 1 | 0 | 6, 7, 0, 1, 2, 3, 4, 5, | 6, 7, 4, 5, 2, 3, 0, 1, |
| 1 | 1 | 1 | 7, 0, 1, 2, 3, 4, 5, 6, | 7, 6, 5, 4, 3, 2, 1, 0, |

Burst Sequence

Full page burst is available only for sequential addressing. The addressing sequence is started from the column address that is asserted by read/write command. And the address is increased one by one. It is back to the address 0 when the address reaches at the end of address 255. "Full page burst" stops the burst read/write with burst stop command.

Power-up Sequence

Power-up sequence

The SDRAM should be goes on the following sequence with power up.

The CLK, CKE, /CS, DQM and DQ pins keep low till power stabilizes.

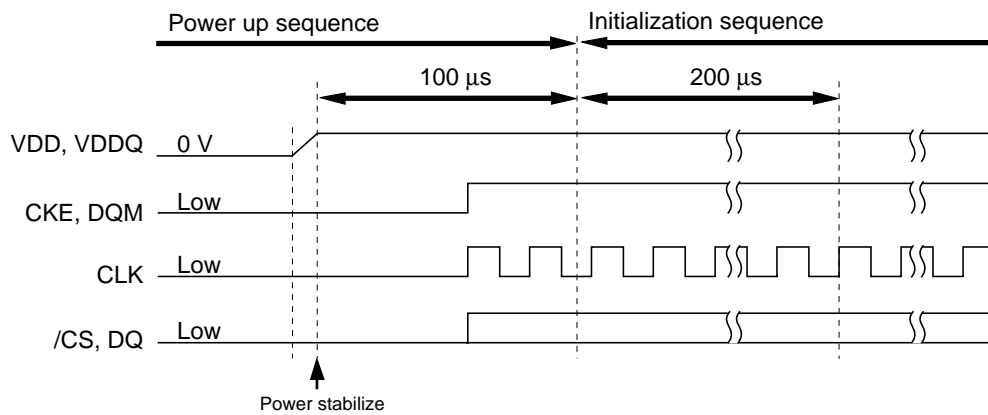
The CLK pin is stabilized within 100 μ s after power stabilizes before the following initialization sequence.

The CKE and DQM is driven to high between power stabilizes and the initialization sequence.

This SDRAM has VDD clamp diodes for CLK, CKE, address, /RAS, /CAS, /WE, /CS, DQM and DQ pins. If these pins go high before power up, the large current flows from these pins to VDD through the diodes.

Initialization sequence

When 200 μ s or more has past after the above power-up sequence, all banks must be precharged using the precharge command (PALL). After tRP delay, set 8 or more auto refresh commands (REF). Set the mode register set command (MRS) to initialize the mode register. We recommend that by keeping DQM and CKE to High, the output buffer becomes High-Z during Initialization sequence, to avoid DQ bus contention on memory system formed with a number of device.



Power-up sequence and Initialization sequence

Operation of the SDRAM

Read/Write Operations

Bank active

Before executing a read or write operation, the corresponding bank and the row address must be activated by the bank active (ACT) command. An interval of tRCD is required between the bank active command input and the following read/write command input.

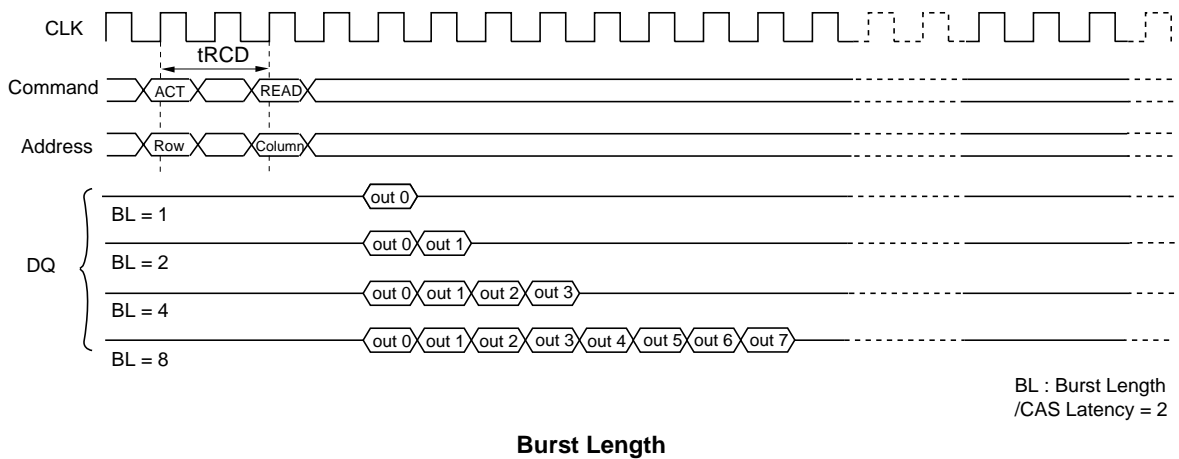
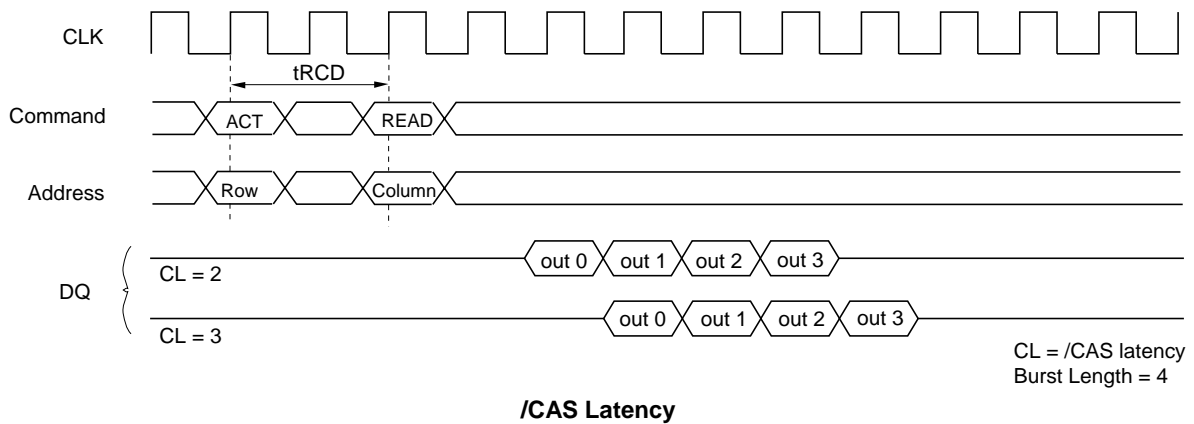
Read operation

A read operation starts when a read command is input. Output buffer becomes Low-Z in the (/CAS Latency - 1) cycle after read command set. The SDRAM can perform a burst read operation.

The burst length can be set to 1, 2, 4 and 8. The start address for a burst read is specified by the column address and the bank select address at the read command set cycle. In a read operation, data output starts after the number of clocks specified by the /CAS Latency. The /CAS Latency can be set to 2 or 3.

When the burst length is 1, 2, 4 and 8 the DOUT buffer automatically becomes High-Z at the next clock after the successive burst-length data has been output.

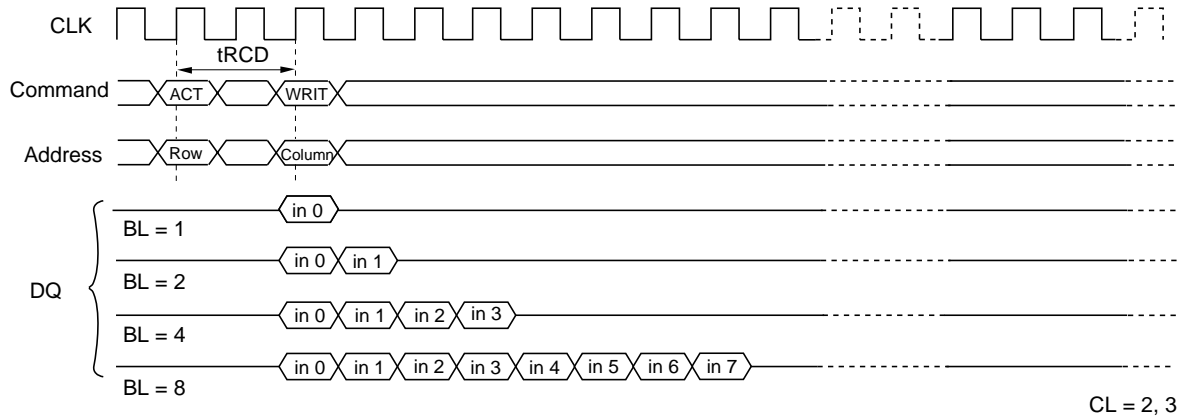
The /CAS latency and burst length must be specified at the mode register.



Write operation

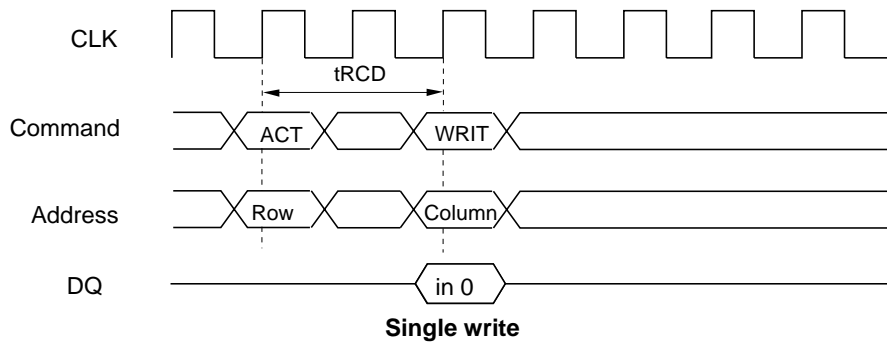
Burst write or single write mode is selected by the OPCODE of the mode register.

1. Burst write: A burst write operation is enabled by setting OPCODE (A9, A8) to (0, 0). A burst write starts in the same clock as a write command set. (The latency of data input is 0 clock.) The burst length can be set to 1, 2, 4 and 8, like burst read operations. The write start address is specified by the column address and the bank select address at the write command set cycle.



Burst write

2. Single write: A single write operation is enabled by setting OPCODE (A9, A8) to (1, 0). In a single write operation, data is only written to the column address and the bank select address specified by the write command set cycle without regard to the burst length setting. (The latency of data input is 0 clock).



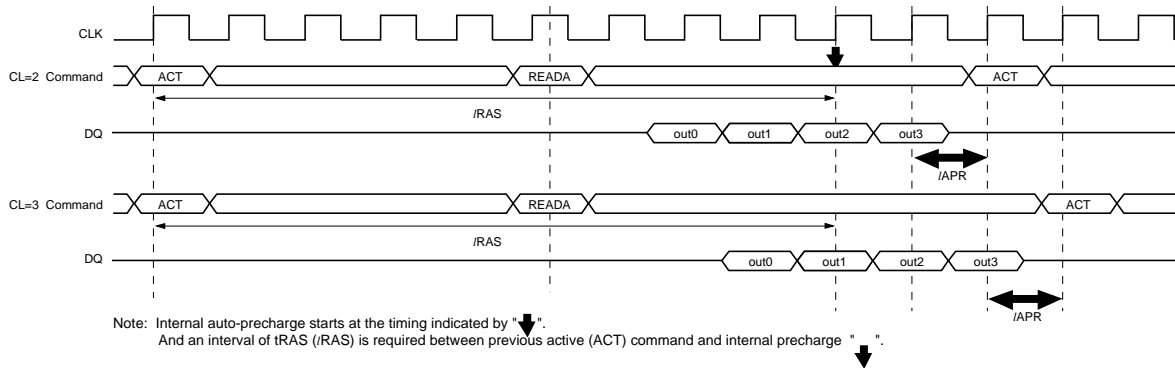
Auto Precharge

Read with auto-precharge

In this operation, since precharge is automatically performed after completing a read operation, a precharge command need not be executed after each read operation. The command executed for the same bank after the execution of this command must be the bank active (ACT) command. In addition, an interval defined by *IAPR* is required before execution of the next command.

[Clock cycle time]

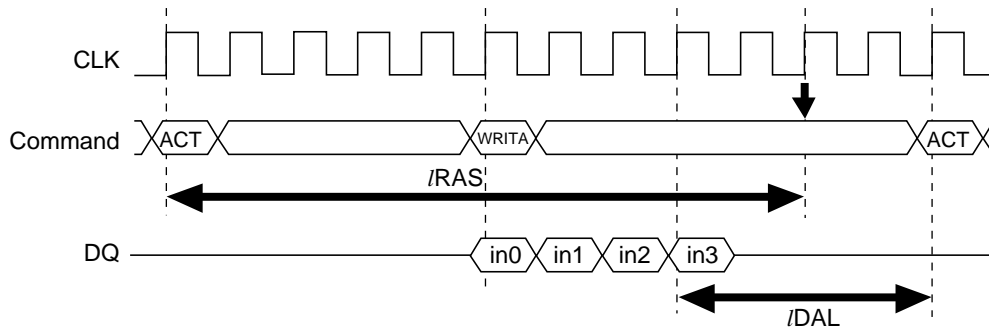
| <i>/CAS</i> latency | Precharge start cycle |
|---------------------|---|
| 3 | 2 cycle before the final data is output |
| 2 | 1 cycle before the final data is output |



Burst Read (BL = 4)

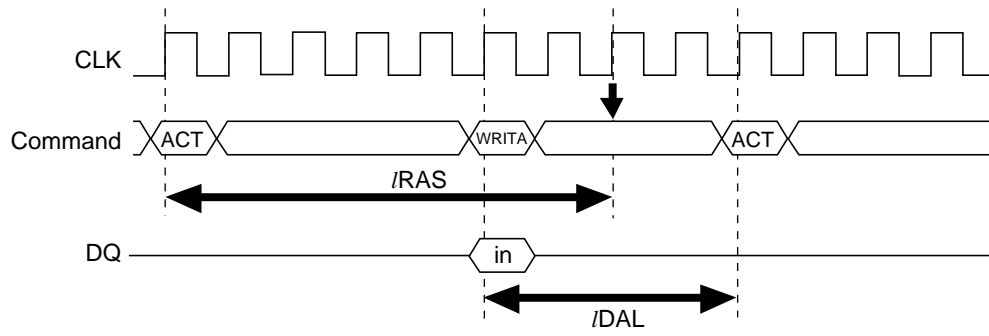
Write with auto-precharge

In this operation, since precharge is automatically performed after completing a burst write or single write operation, a precharge command need not be executed after each write operation. The command executed for the same bank after the execution of this command must be the bank active (ACT) command. In addition, an interval of *IDAL* is required between the final valid data input and input of next command.



Note: Internal auto-precharge starts at the timing indicated by "↓".
and an interval of *tRAS* (*I/RAS*) is required between previous active (ACT) command and internal precharge "↓".

Burst Write (BL = 4)

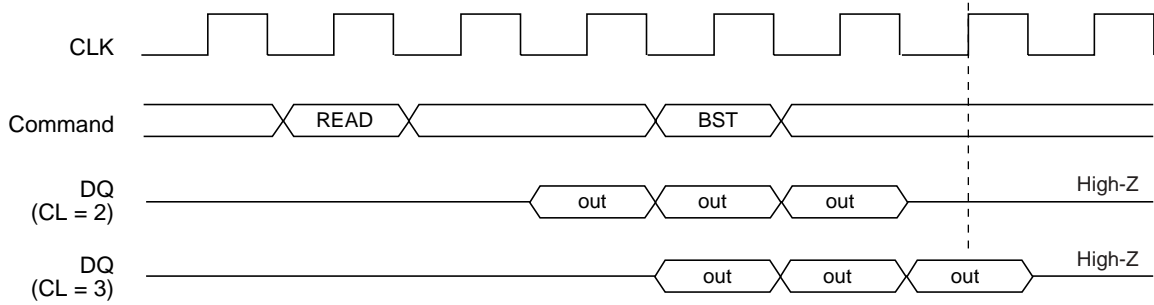


Note: Internal auto-precharge starts at the timing indicated by "↓".
 and an interval of tRAS (/RAS) is required between previous active (ACT) command
 and internal precharge "↓".

Single Write

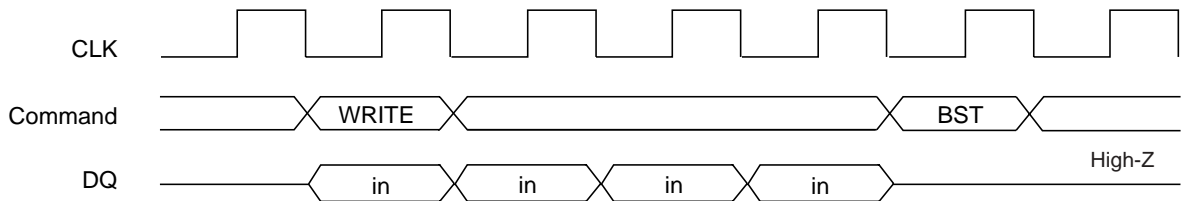
Burst Stop Command

During a read cycle, when the burst stop command is issued, the burst read data are terminated and the data bus goes to High-Z after the /CAS latency from the burst stop command.



Burst Stop at Read

During a write cycle, when the burst stop command is issued, the burst write data are terminated and data bus goes to High-Z at the same clock with the burst stop command.

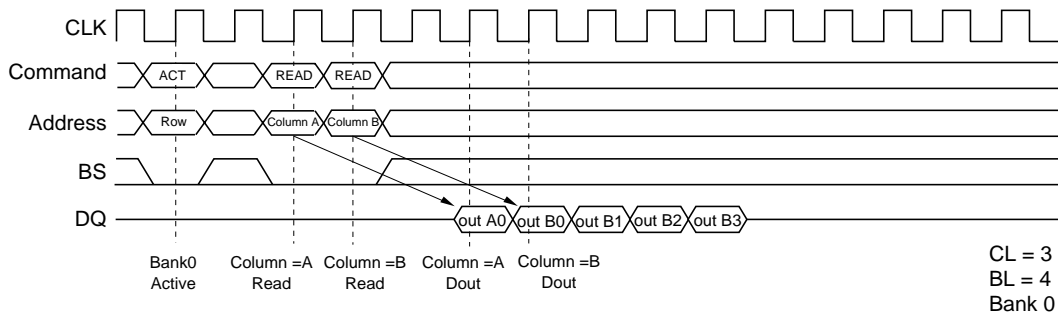


Burst Stop at Write

Command Intervals

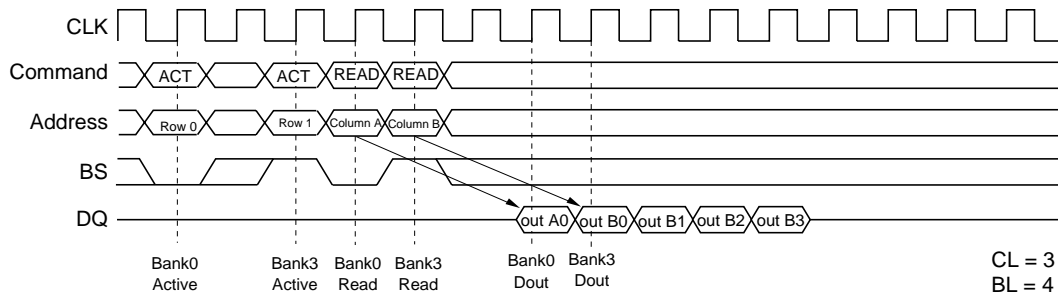
Read command to Read command interval

1. Same bank, same ROW address: When another read command is executed at the same ROW address of the same bank as the preceding read command execution, the second read can be performed after an interval of no less than 1 clock. Even when the first command is a burst read that is not yet finished, the data read by the second command will be valid.



READ to READ Command Interval (same ROW address in same bank)

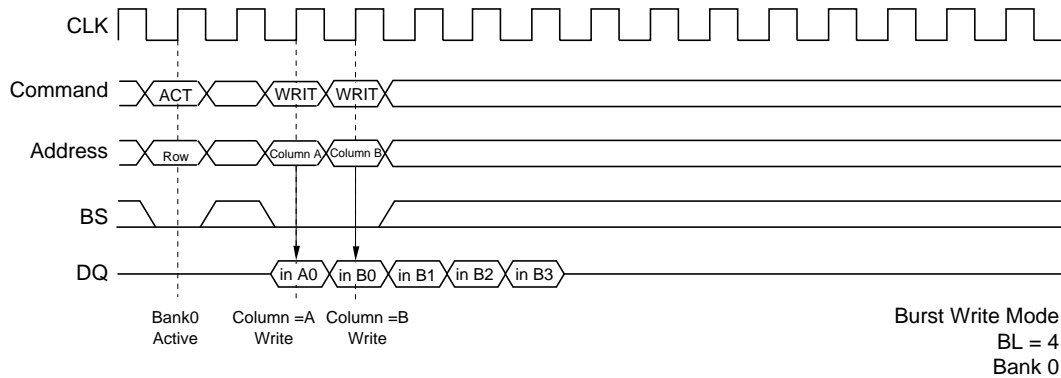
2. Same bank, different ROW address: When the ROW address changes on same bank, consecutive read commands cannot be executed; it is necessary to separate the two read commands with a precharge command and a bank active command.
3. Different bank: When the bank changes, the second read can be performed after an interval of no less than 1 clock, provided that the other bank is in the bank active state. Even when the first command is a burst read that is not yet finished, the data read by the second command will be valid.



READ to READ Command Interval (different bank)

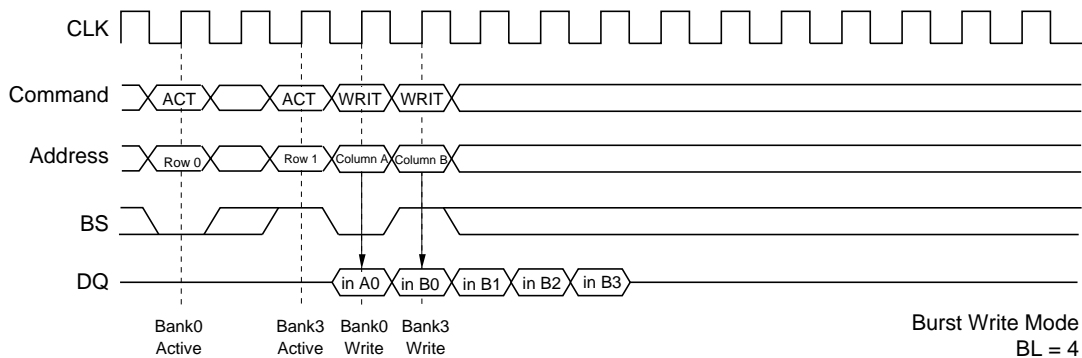
Write command to Write command interval

1. Same bank, same ROW address: When another write command is executed at the same ROW address of the same bank as the preceding write command, the second write can be performed after an interval of no less than 1 clock. In the case of burst writes, the second write command has priority.



WRITE to WRITE Command Interval (same ROW address in same bank)

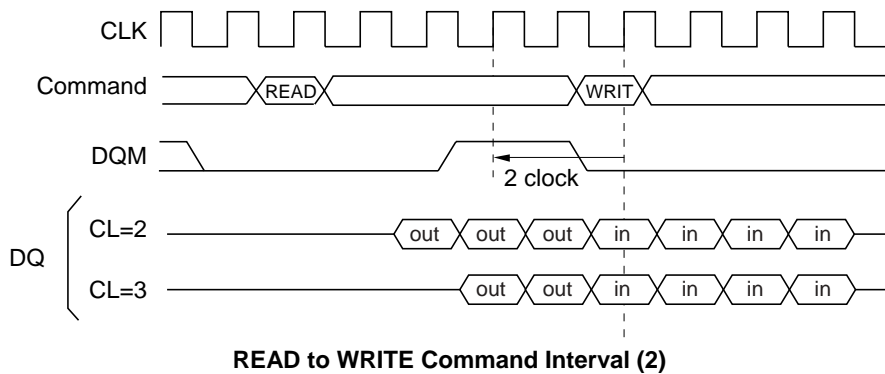
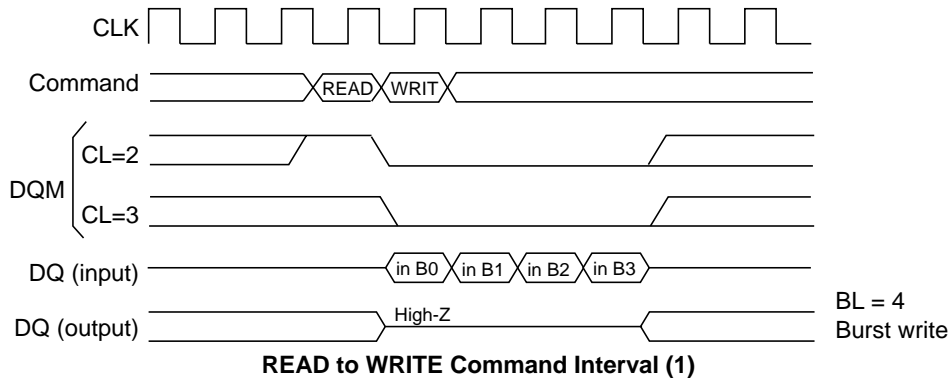
2. Same bank, different ROW address: When the ROW address changes, consecutive write commands cannot be executed; it is necessary to separate the two write commands with a precharge command and a bank active command.
3. Different bank: When the bank changes, the second write can be performed after an interval of no less than 1 clock, provided that the other bank is in the bank active state. In the case of burst write, the second write command has priority.



WRITE to WRITE Command Interval (different bank)

Read command to Write command interval

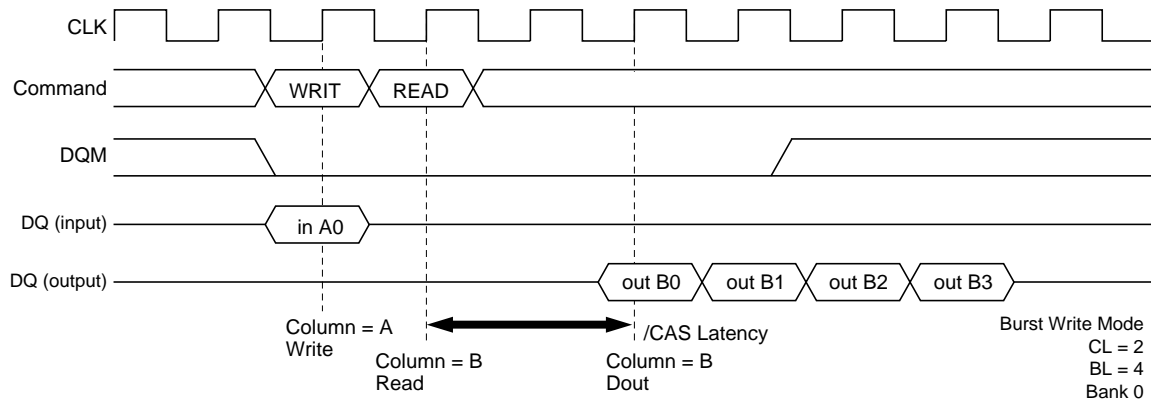
1. Same bank, same ROW address: When the write command is executed at the same ROW address of the same bank as the preceding read command, the write command can be performed after an interval of no less than 1 clock. However, DQM must be set High so that the output buffer becomes High-Z before data input.



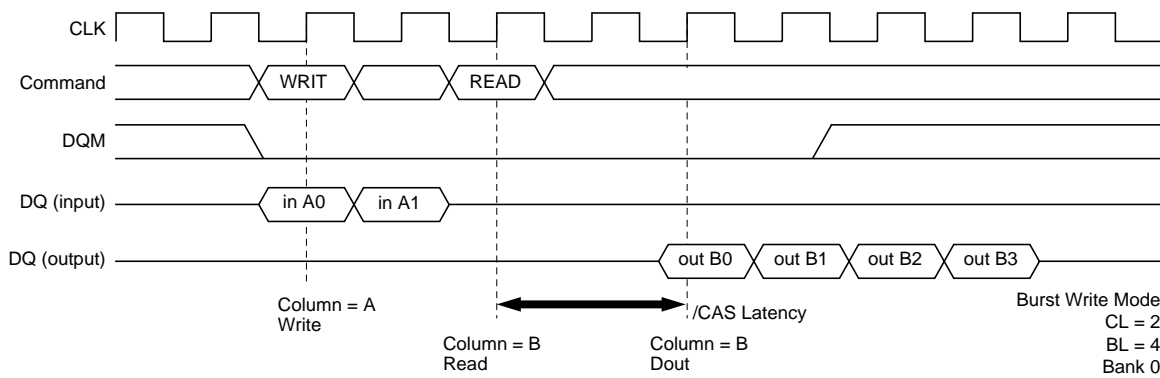
2. Same bank, different ROW address: When the ROW address changes, consecutive write commands cannot be executed; it is necessary to separate the two commands with a precharge command and a bank active command.
3. Different bank: When the bank changes, the write command can be performed after an interval of no less than 1 cycle, provided that the other bank is in the bank active state. However, DQM must be set High so that the output buffer becomes High-Z before data input.

Write command to Read command interval:

1. Same bank, same ROW address: When the read command is executed at the same ROW address of the same bank as the preceding write command, the read command can be performed after an interval of no less than 1 clock. However, in the case of a burst write, data will continue to be written until one clock before the read command is executed.



WRITE to READ Command Interval (1)

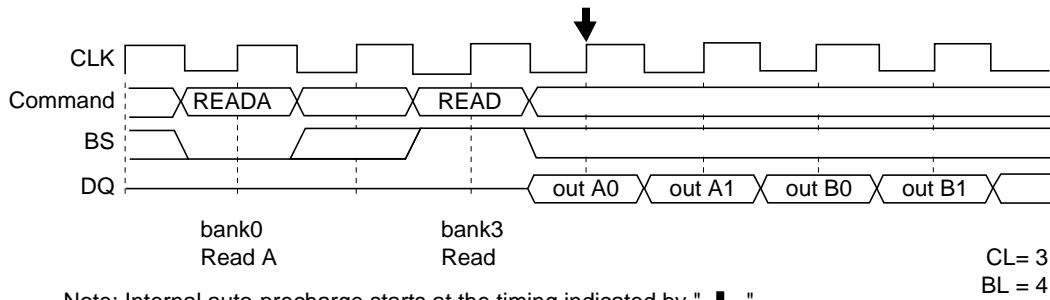


WRITE to READ Command Interval (2)

2. Same bank, different ROW address: When the ROW address changes, consecutive read commands cannot be executed; it is necessary to separate the two commands with a precharge command and a bank active command.
3. Different bank: When the bank changes, the read command can be performed after an interval of no less than 1 clock, provided that the other bank is in the bank active state. However, in the case of a burst write, data will continue to be written until one clock before the read command is executed (as in the case of the same bank and the same address).

Read with auto precharge to Read command interval

1. Different bank: When some banks are in the active state, the second read command (another bank) is executed. Even when the first read with auto-precharge is a burst read that is not yet finished, the data read by the second command is valid. The internal auto-precharge of one bank starts at the next clock of the second command.



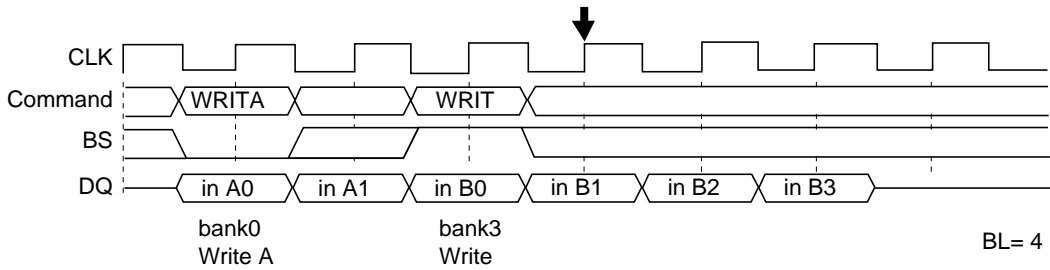
Note: Internal auto-precharge starts at the timing indicated by " ↓ ".

Read with Auto Precharge to Read Command Interval (Different bank)

2. Same bank: The consecutive read command (the same bank) is illegal.

Write with auto precharge to Write command interval

1. Different bank: When some banks are in the active state, the second write command (another bank) is executed. In the case of burst writes, the second write command has priority. The internal auto-precharge of one bank starts 2 clocks later from the second command.



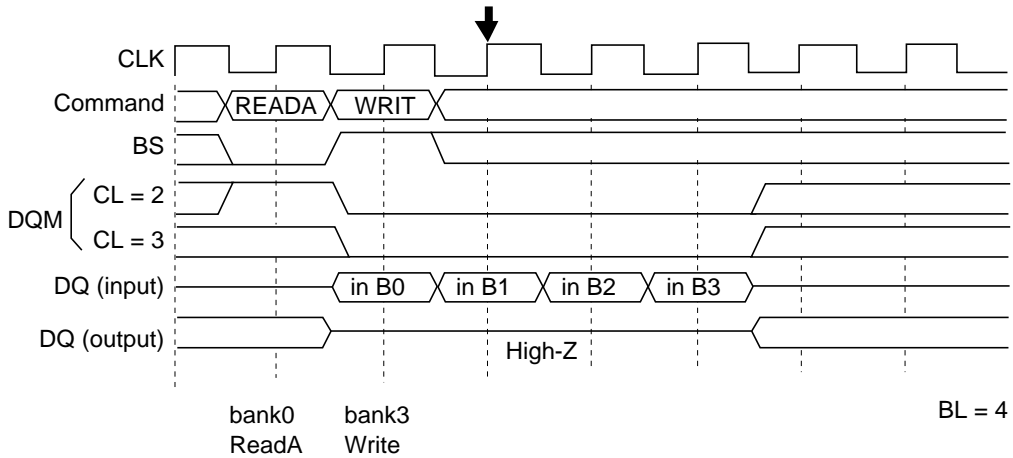
Note: Internal auto-precharge starts at the timing indicated by " ↓ ".

Write with Auto Precharge to Write Command Interval (Different bank)

2. Same bank: The consecutive write command (the same bank) is illegal.

Read with auto precharge to Write command interval

1. Different bank: When some banks are in the active state, the second write command (another bank) is executed. However, DQM must be set High so that the output buffer becomes High-Z before data input. The internal auto-precharge of one bank starts at the next clock of the second command.



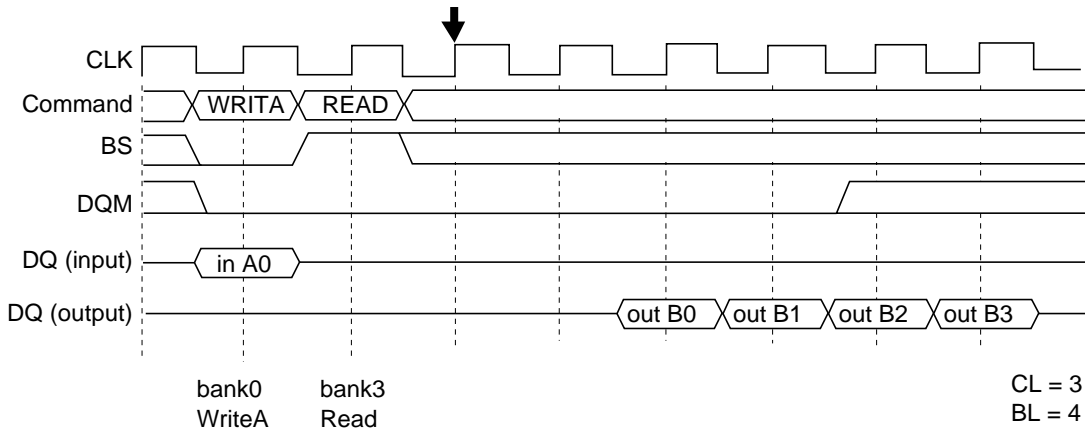
Note: Internal auto-precharge starts at the timing indicated by " ↓ ".

Read with Auto Precharge to Write Command Interval (Different bank)

2. Same bank: The consecutive write command from read with auto precharge (the same bank) is illegal. It is necessary to separate the two commands with a bank active command.

Write with auto precharge to Read command interval

1. Different bank: When some banks are in the active state, the second read command (another bank) is executed. However, in case of a burst write, data will continue to be written until one clock before the read command is executed. The internal auto-precharge of one bank starts at 2 clocks later from the second command.



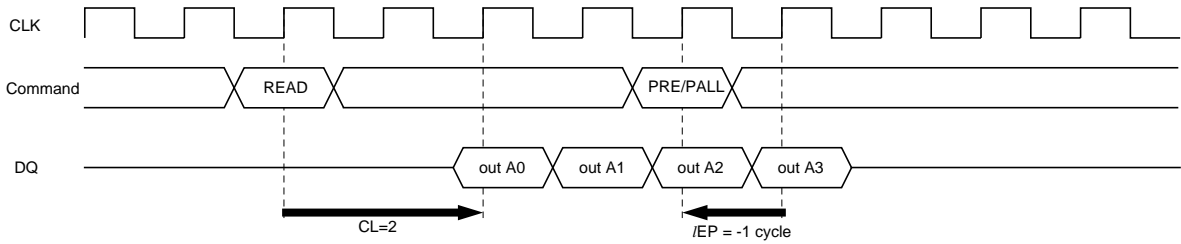
Note: Internal auto-precharge starts at the timing indicated by " ↓ ".

Write with Auto Precharge to Read Command Interval (Different bank)

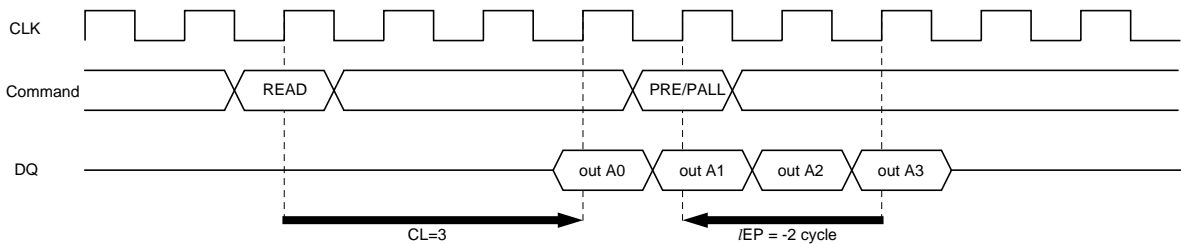
2. Same bank: The consecutive read command from write with auto precharge (the same bank) is illegal. It is necessary to separate the two commands with a bank active command.

Read command to Precharge command interval (same bank)

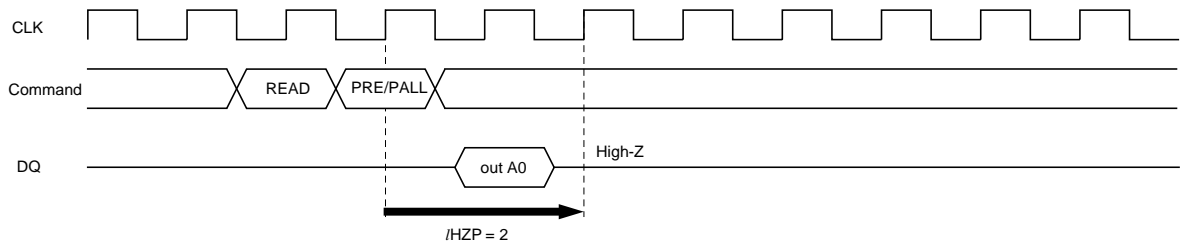
When the precharge command is executed for the same bank as the read command that preceded it, the minimum interval between the two commands is one clock. However, since the output buffer then becomes High-Z after the clocks defined by *t*HZP, there is a case of interruption to burst read data output will be interrupted, if the precharge command is input during burst read. To read all data by burst read, the clocks defined by *t*EP must be assured as an interval from the final data output to precharge command execution.



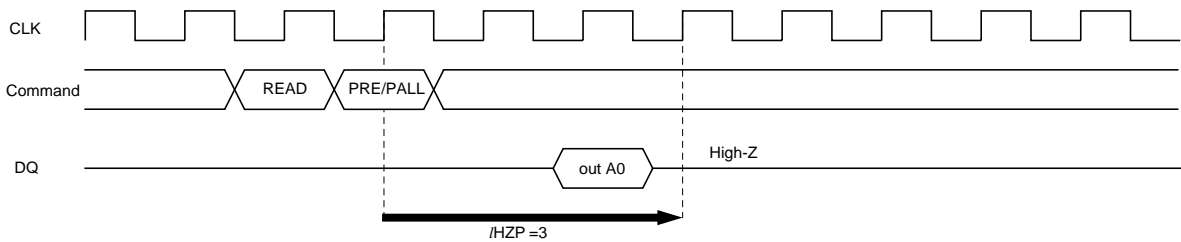
READ to PRECHARGE Command Interval (same bank): To output all data (CL = 2, BL = 4)



READ to PRECHARGE Command Interval (same bank): To output all data (CL = 3, BL = 4)



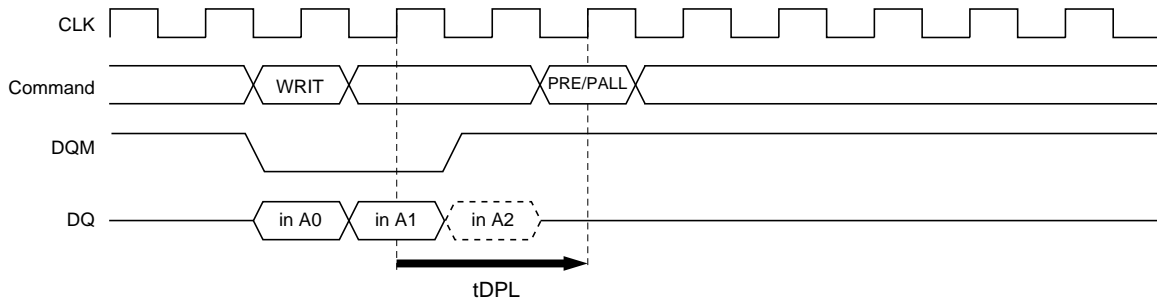
READ to PRECHARGE Command Interval (same bank): To stop output data (CL = 2, BL = 1, 2, 4, 8)



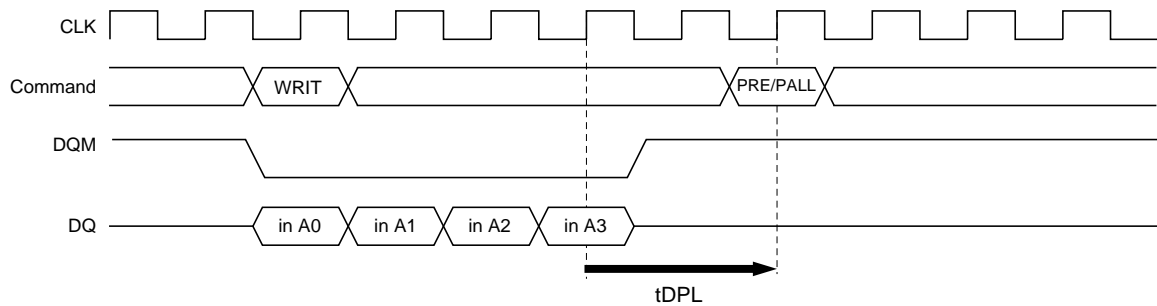
READ to PRECHARGE Command Interval (same bank): To stop output data (CL = 3, BL = 1, 2, 4, 8)

Write command to Precharge command interval (same bank)

When the precharge command is executed for the same bank as the write command that preceded it, the minimum interval between the two commands is 1 clock. However, if the burst write operation is unfinished, the input data must be masked by means of DQM for assurance of the clock defined by tDPL.



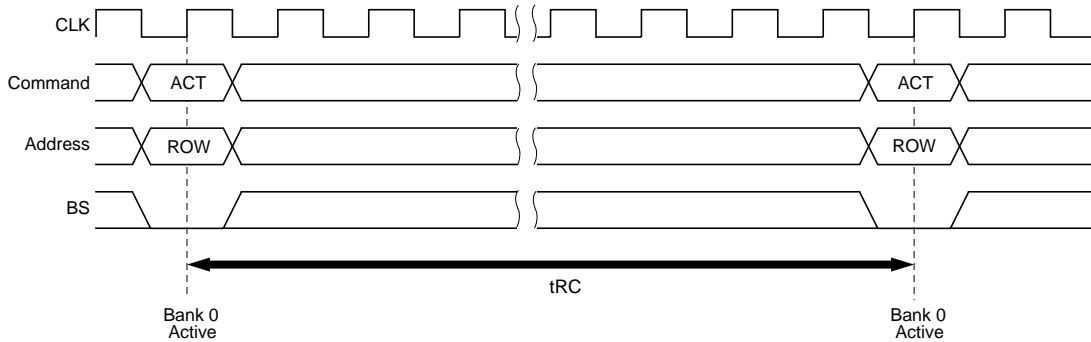
WRITE to PRECHARGE Command Interval (same bank) (BL = 4 (To stop write operation))



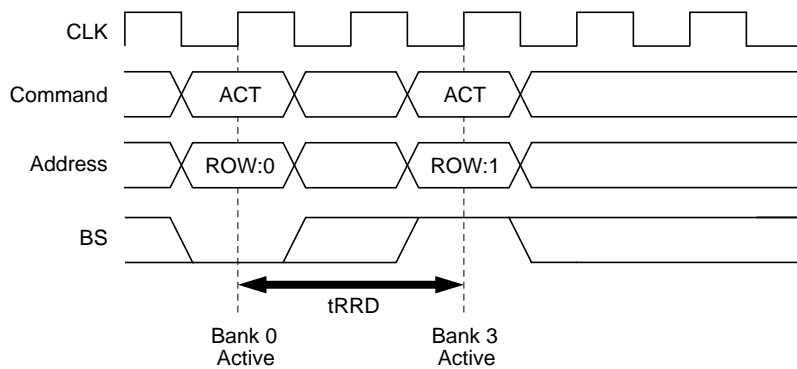
WRITE to PRECHARGE Command Interval (same bank) (BL = 4 (To write all data))

Bank active command interval

1. Same bank: The interval between the two bank active commands must be no less than t_{RC} .
2. In the case of different bank active commands: The interval between the two bank active commands must be no less than t_{RRD} .



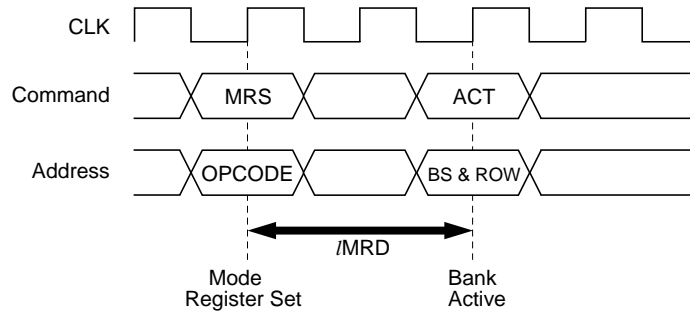
Bank Active to Bank Active for Same Bank



Bank Active to Bank Active for Different Bank

Mode register set to Bank active command interval

The interval between setting the mode register and executing a bank active command must be no less than t_{MRD} .



Mode register set to Bank active command interval

DQM Control

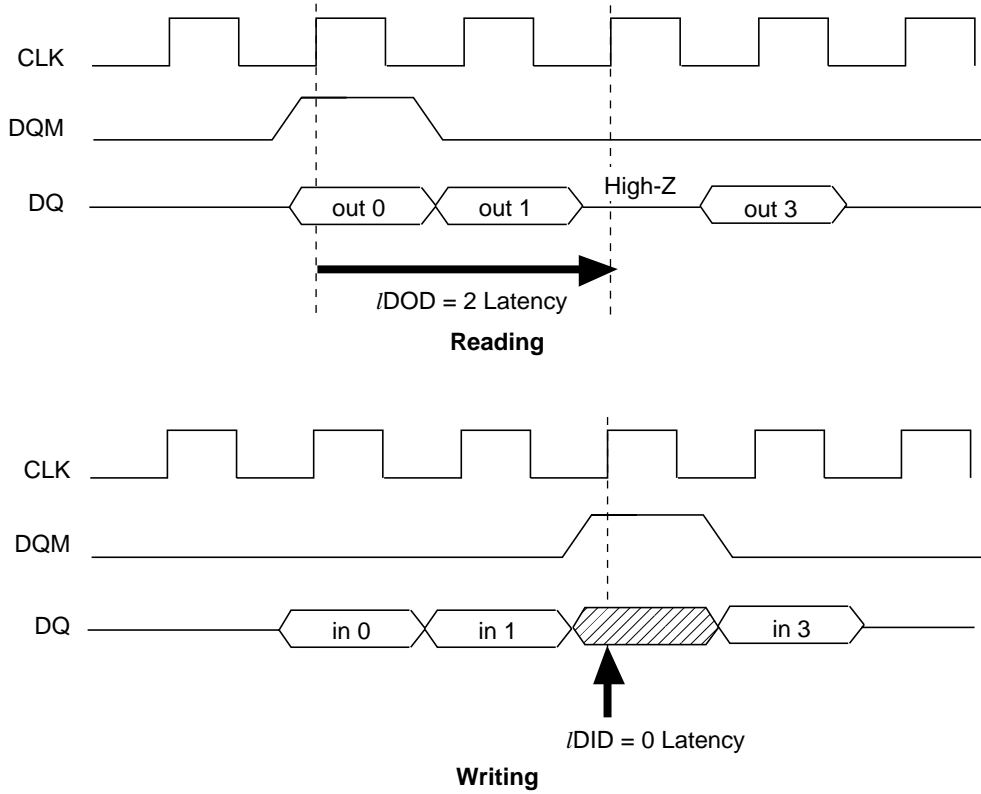
The DQM mask the DQ data. The timing of DQM is different during reading and writing.

Reading

When data is read, the output buffer can be controlled by DQM. By setting DQM to Low, the output buffer becomes Low-Z, enabling data output. By setting DQM to High, the output buffer becomes High-Z, and the corresponding data is not output. However, internal reading operations continue. The latency of DQM during reading is 2 clocks.

Writing

Input data can be masked by DQM. By setting DQM to Low, data can be written. In addition, when DQM is set to High, the corresponding data is not written, and the previous data is held. The latency of DQM during writing is 0 clock.



Refresh**Auto-refresh**

All the banks must be precharged before executing an auto-refresh command. Since the auto-refresh command updates the internal counter every time it is executed and determines the banks and the ROW addresses to be refreshed, external address specification is not required. The refresh cycles are required to refresh all the ROW addresses within tREF (max.). The output buffer becomes High-Z after auto-refresh start. In addition, since a precharge has been completed by an internal operation after the auto-refresh, an additional precharge operation by the precharge command is not required.

Self-refresh

After executing a self-refresh command, the self-refresh operation continues while CKE is held Low. During self-refresh operation, all ROW addresses are refreshed by the internal refresh timer. A self-refresh is terminated by a self-refresh exit command. Before and after self-refresh mode, execute auto-refresh to all refresh addresses in or within tREF (max.) period on the condition 1 and 2 below.

1. Enter self-refresh mode within time as below* after either burst refresh or distributed refresh at equal interval to all refresh addresses are completed.
2. Start burst refresh or distributed refresh at equal interval to all refresh addresses within time as below*after exiting from self-refresh mode.

Note: tREF (max.) / refresh cycles.

Others**Power-down mode**

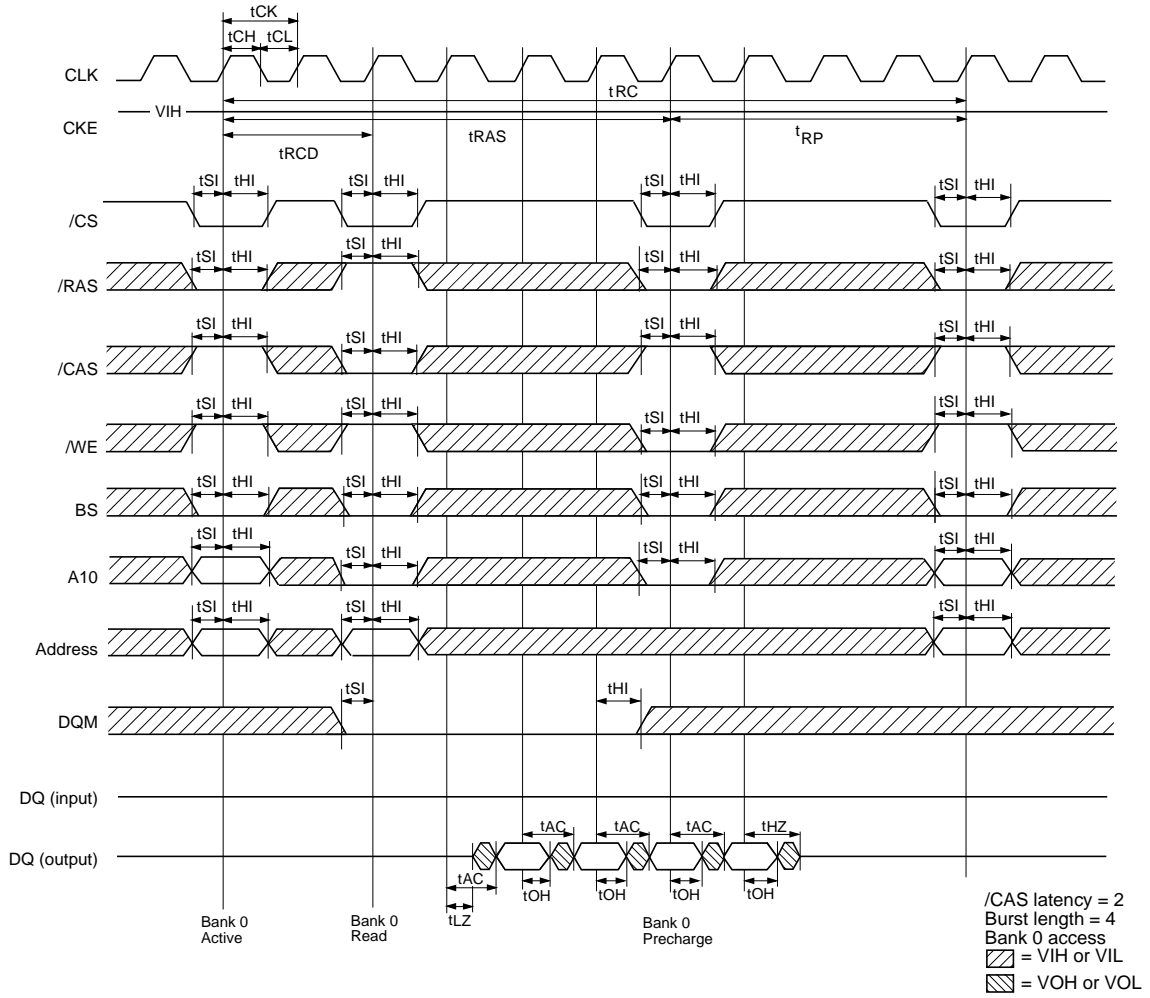
The SDRAM enters power-down mode when CKE goes Low in the IDLE state. In power down mode, power consumption is suppressed by deactivating the input initial circuit. Power down mode continues while CKE is held Low. In addition, by setting CKE to High, the SDRAM exits from the power down mode, and command input is enabled from the next clock. In this mode, internal refresh is not performed.

Clock suspend mode

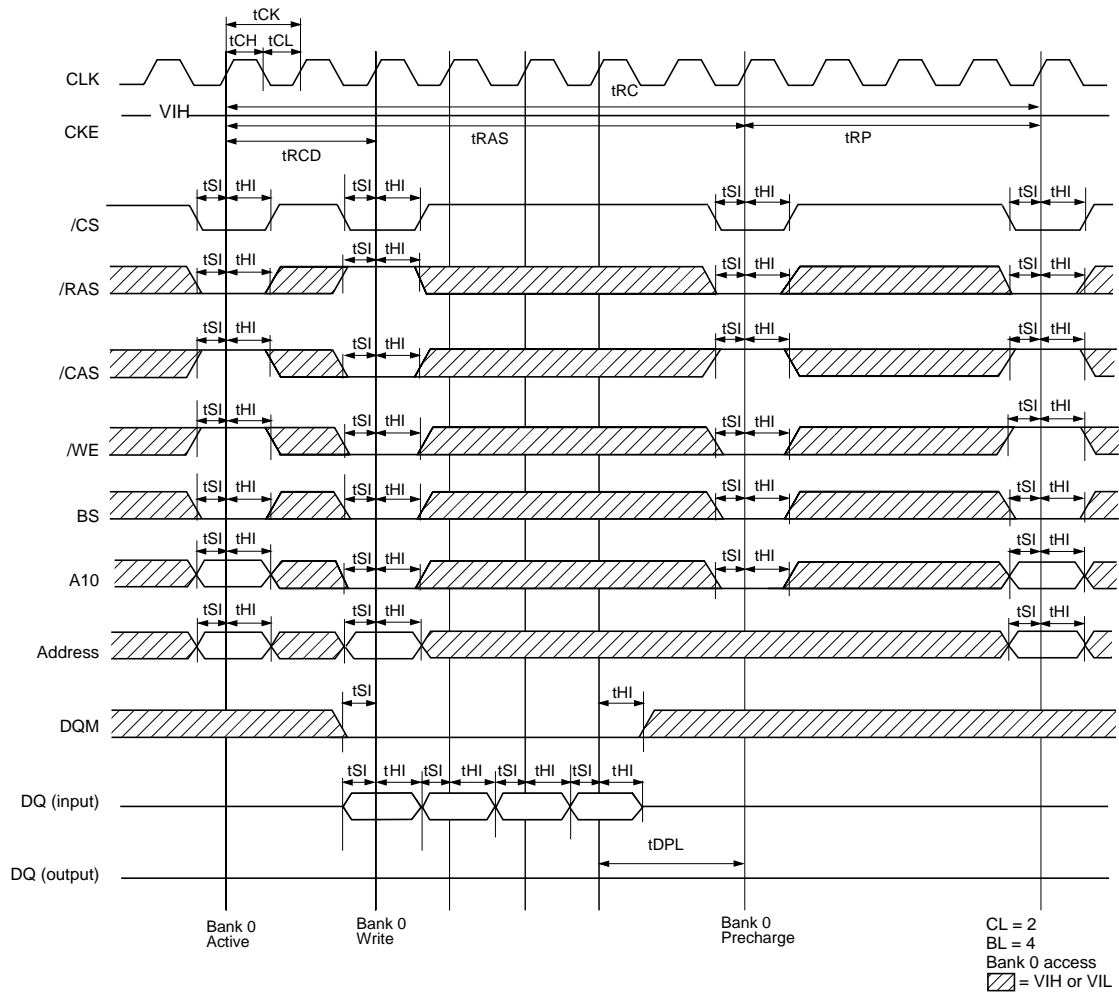
By driving CKE to Low during a bank active or read/write operation, the SDRAM enters clock suspend mode. During clock suspend mode, external input signals are ignored and the internal state is maintained. When CKE is driven High, the SDRAM terminates clock suspend mode, and command input is enabled from the next clock. For details, refer to the "CKE Truth Table".

Timing Waveforms

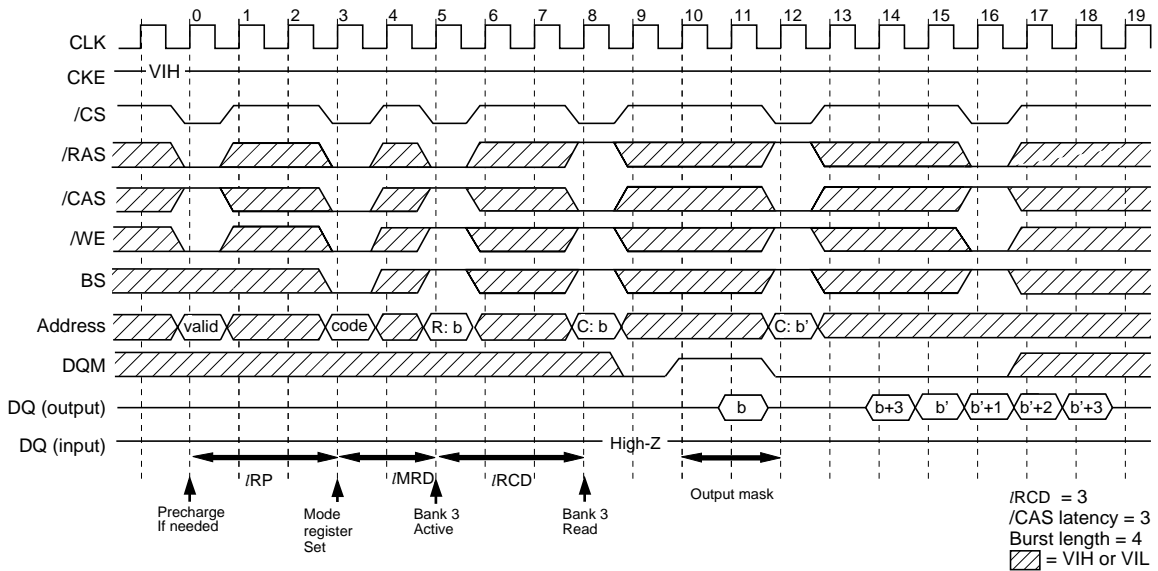
Read Cycle



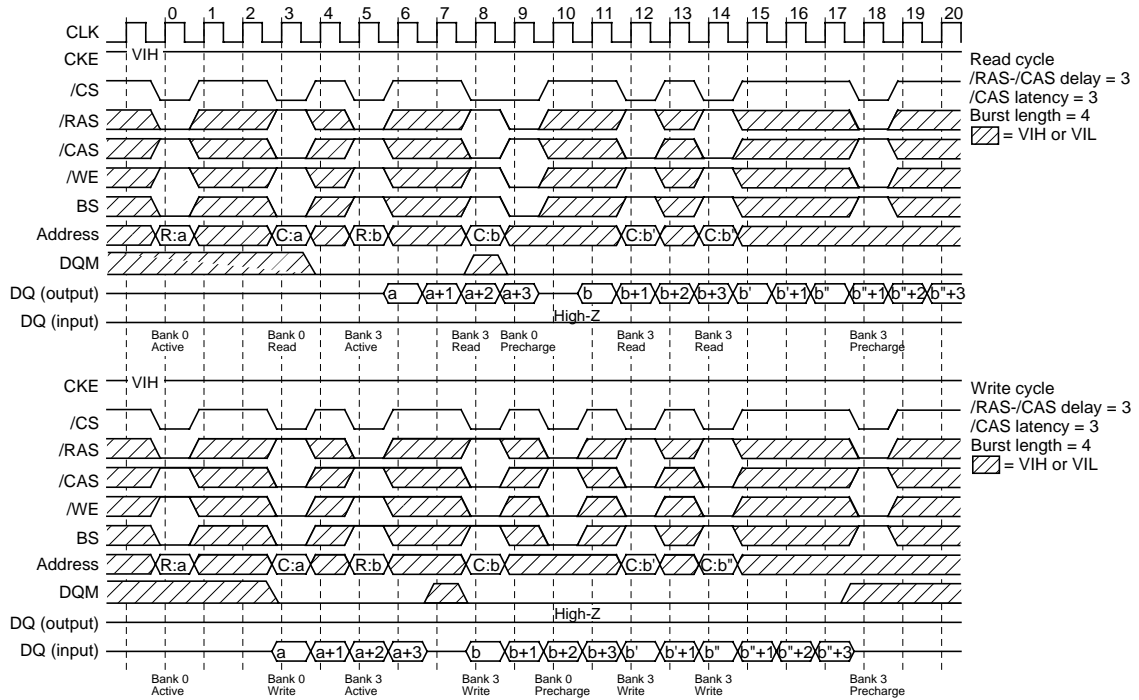
Write Cycle



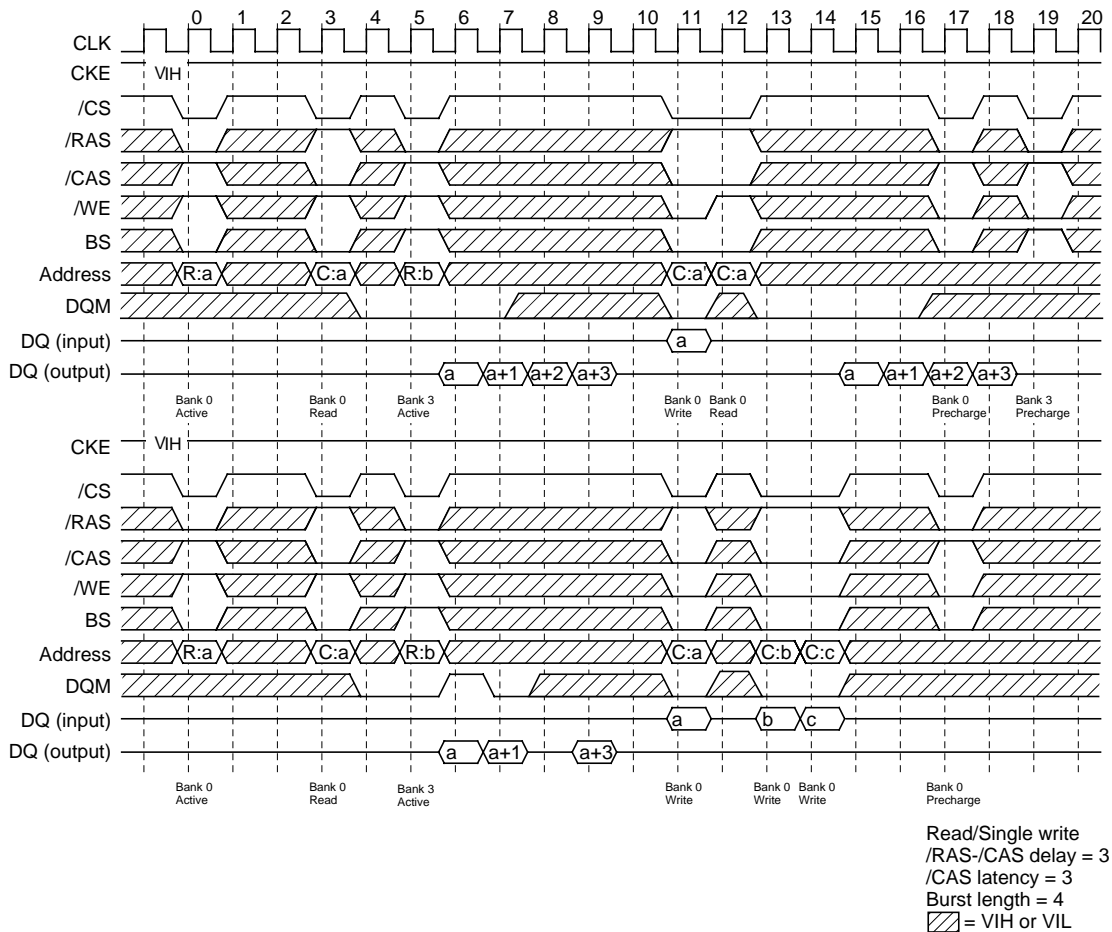
Mode Register Set Cycle



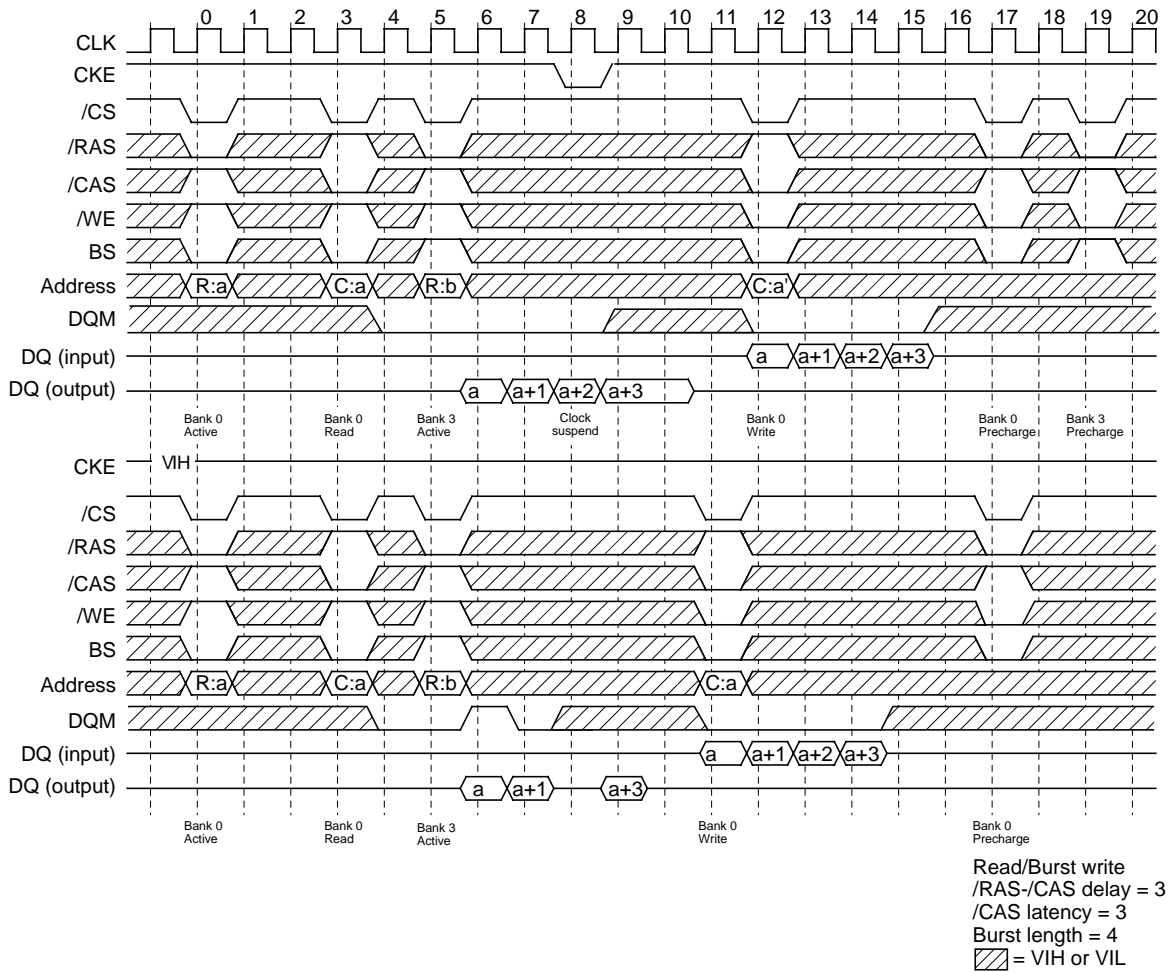
Read Cycle/Write Cycle



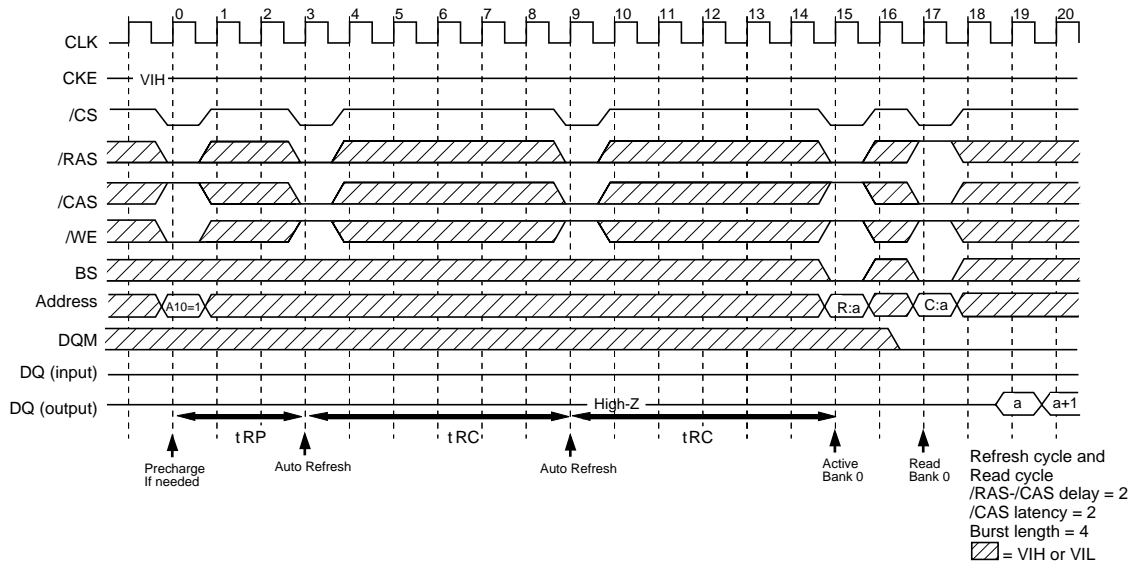
Read/Single Write Cycle



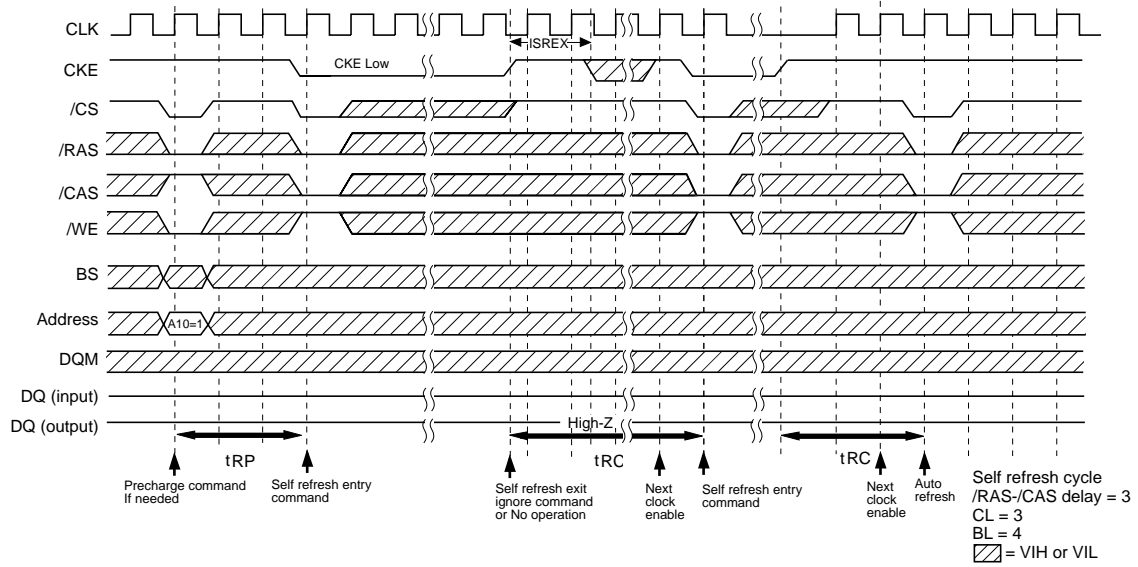
Read/Burst Write Cycle



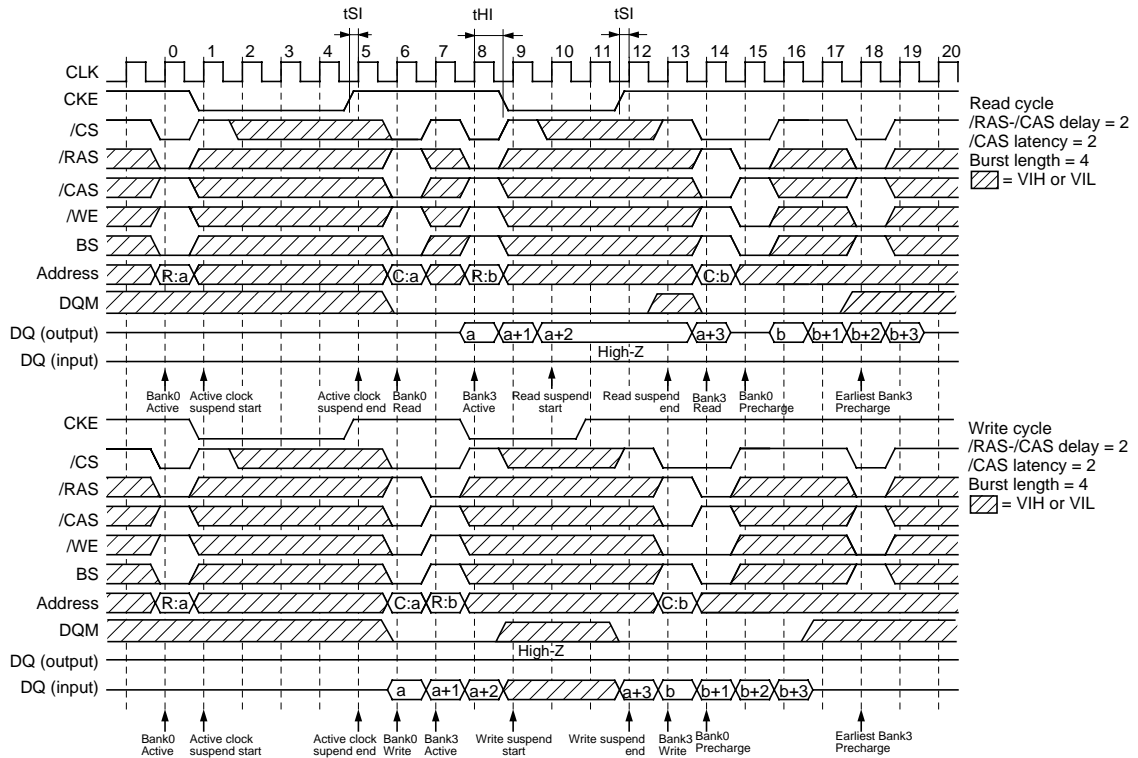
Auto Refresh Cycle



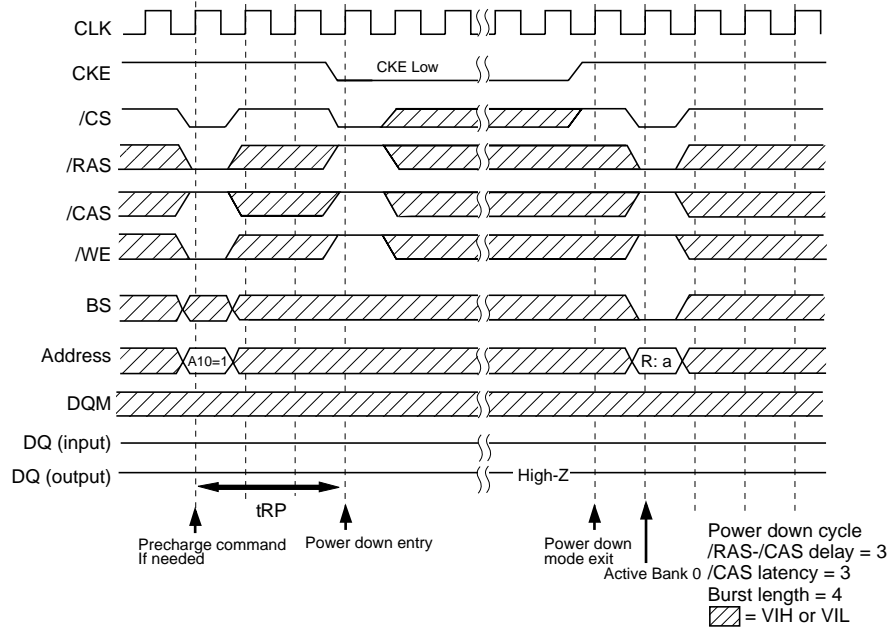
Self Refresh Cycle



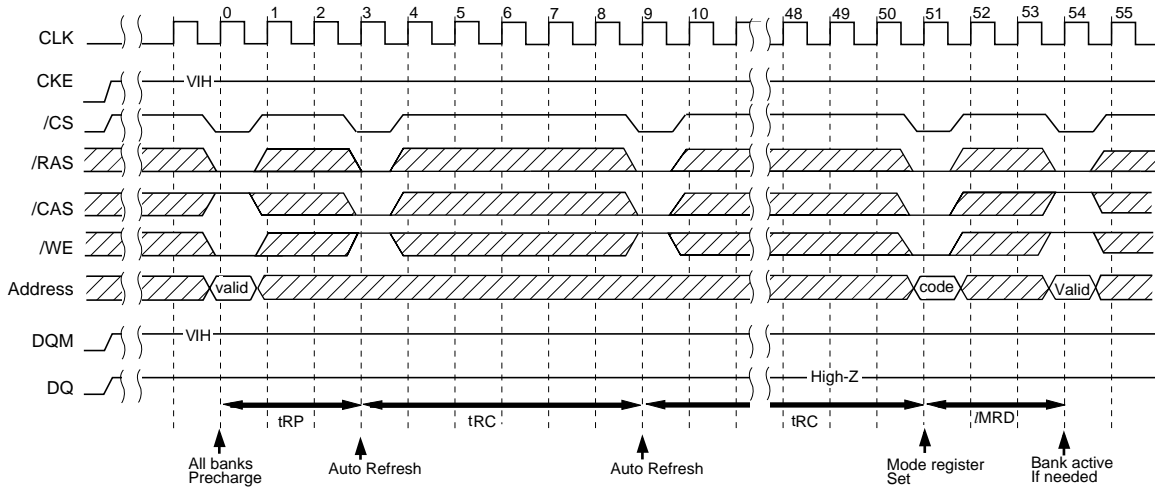
Clock Suspend Mode



Power Down Mode



Initialization Sequence

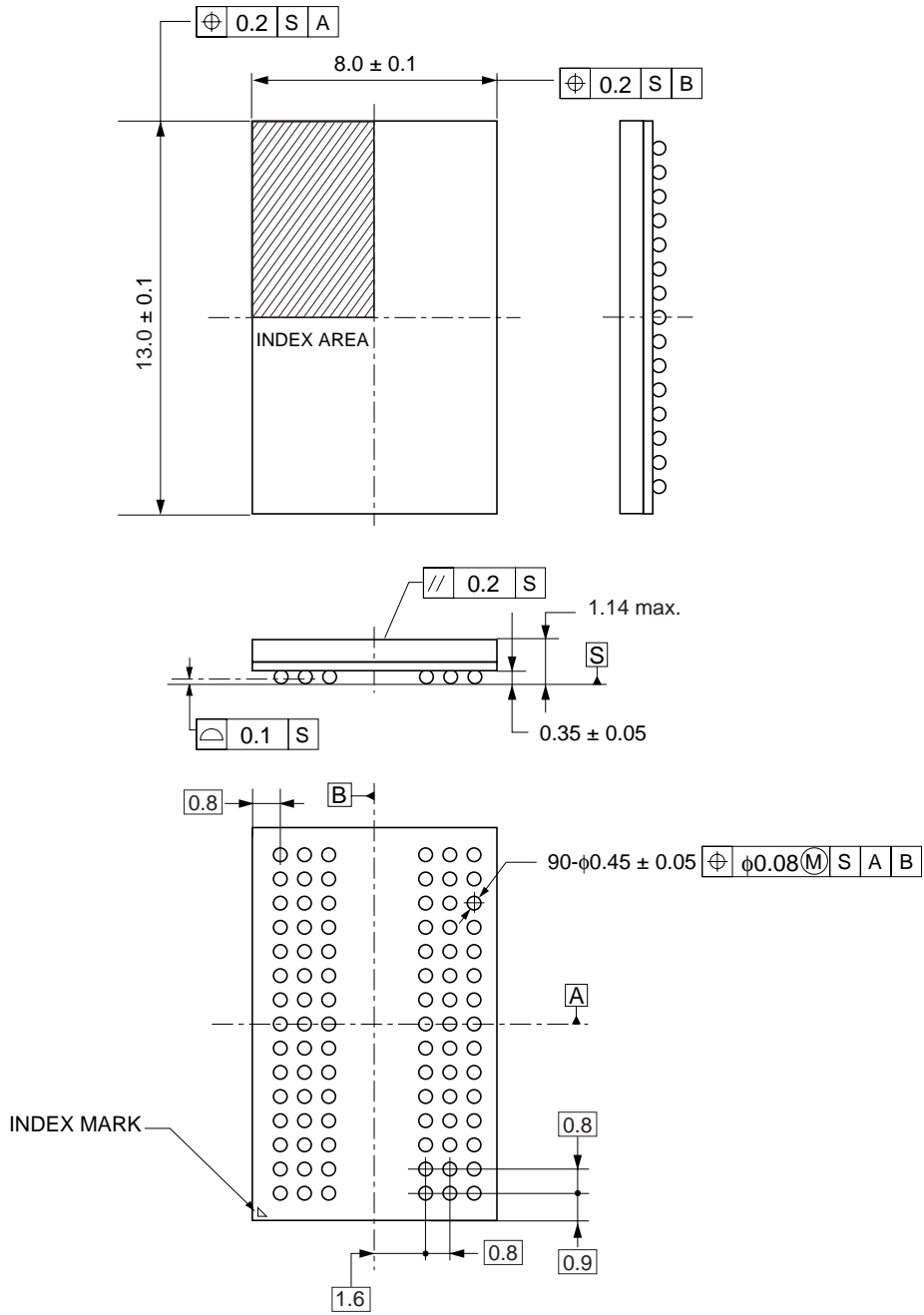


Package Drawing

90-ball FBGA

Solder ball: Lead free (Sn-Ag-Cu)

Unit: mm



ECA-TS2-0096-01

Recommended Soldering Conditions

Please consult with our sales offices for soldering conditions of the EDS6432AFBH and EDS6432CFBH.

Type of Surface Mount Device

EDS6432AFBH, EDS6432CFBH: 90-ball FBGA < Lead free (Sn-Ag-Cu) >

NOTES FOR CMOS DEVICES**① PRECAUTION AGAINST ESD FOR MOS DEVICES**

Exposing the MOS devices to a strong electric field can cause destruction of the gate oxide and ultimately degrade the MOS devices operation. Steps must be taken to stop generation of static electricity as much as possible, and quickly dissipate it, when once it has occurred. Environmental control must be adequate. When it is dry, humidifier should be used. It is recommended to avoid using insulators that easily build static electricity. MOS devices must be stored and transported in an anti-static container, static shielding bag or conductive material. All test and measurement tools including work bench and floor should be grounded. The operator should be grounded using wrist strap. MOS devices must not be touched with bare hands. Similar precautions need to be taken for PW boards with semiconductor MOS devices on it.

② HANDLING OF UNUSED INPUT PINS FOR CMOS DEVICES

No connection for CMOS devices input pins can be a cause of malfunction. If no connection is provided to the input pins, it is possible that an internal input level may be generated due to noise, etc., hence causing malfunction. CMOS devices behave differently than Bipolar or NMOS devices. Input levels of CMOS devices must be fixed high or low by using a pull-up or pull-down circuitry. Each unused pin should be connected to V_{DD} or GND with a resistor, if it is considered to have a possibility of being an output pin. The unused pins must be handled in accordance with the related specifications.

③ STATUS BEFORE INITIALIZATION OF MOS DEVICES

Power-on does not necessarily define initial status of MOS devices. Production process of MOS does not define the initial operation status of the device. Immediately after the power source is turned ON, the MOS devices with reset function have not yet been initialized. Hence, power-on does not guarantee output pin levels, I/O settings or contents of registers. MOS devices are not initialized until the reset signal is received. Reset operation must be executed immediately after power-on for MOS devices having reset function.

CME0107

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[Product usage]

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[Usage environment]

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